

Advanced SANS Methods

Andrew Jackson

SwedNess SANS Course 2021

Lecture 8

Outline

- A) Measuring Larger Structures
- B) Measuring Surface Structures
- C) Measuring Time Dependent Structure
- D) Measuring in Real Space

A) Measuring Larger Structures

Measuring Larger Structures

Exercise

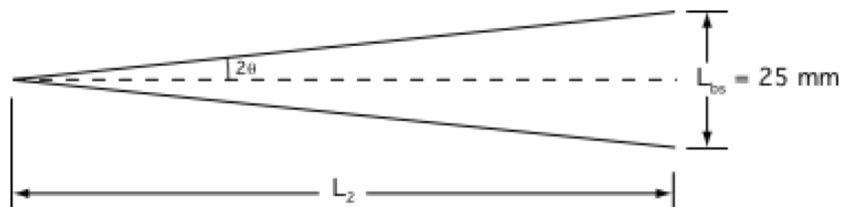
Based on what you have learned, how can we design or configure a SANS instrument to measure larger objects?

Measuring Larger Structures

Exercise

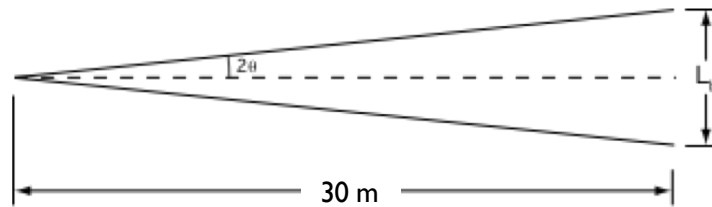
Based on what you have learned, how can we design or configure a SANS instrument to measure larger objects?

(A) Increase Distance at a given Beam Size



Calculate the required L_2 to reach $Q = 3 \times 10^{-5} \text{ \AA}^{-1}$ using neutrons with a wavelength of 4 \AA

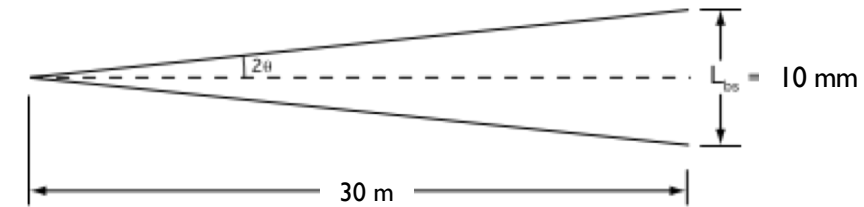
(B) Decrease Beam Size at a given Distance



Calculate the required L_{bs} to reach $Q = 1 \times 10^{-5} \text{ \AA}^{-1}$ using neutrons with a wavelength of 4 \AA .

Assuming $L_1 = L_2$, what aperture sizes would you need to obtain this L_{bs} value?

(C) Increase Wavelength at a given Beam Size and Distance



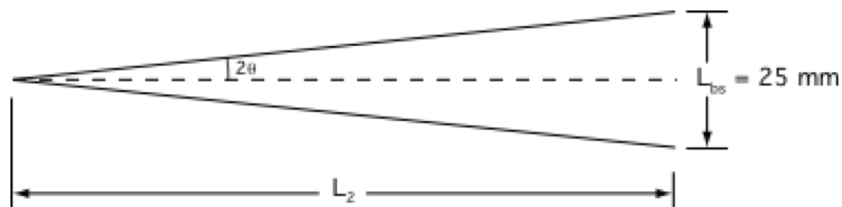
Calculate the minimum Q accessible using neutrons with a wavelength of 20 \AA .

Measuring Larger Structures

Exercise

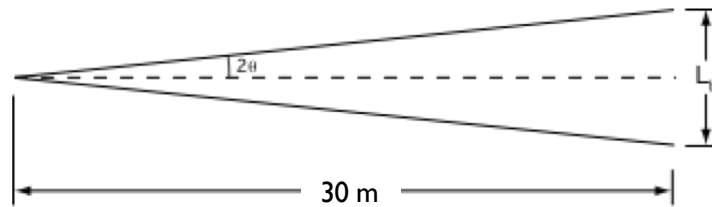
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(A) Increase Distance at a given Beam Size



Calculate the required L_2 to reach $Q = 3 \times 10^{-5} \text{ \AA}^{-1}$ using neutrons with a wavelength of 4 \AA

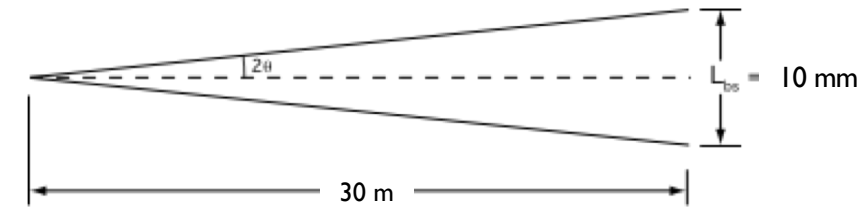
(B) Decrease Beam Size at a given Distance



Calculate the required L_{bs} to reach $Q = 1 \times 10^{-4} \text{ \AA}^{-1}$ using neutrons with a wavelength of 4 \AA .

Assuming $L_1 = L_2$, what aperture sizes would you need to obtain this L_{bs} value?

(C) Increase Wavelength at a given Beam Size and Distance



Calculate the minimum Q accessible using neutrons with a wavelength of 20 \AA .

HINTS!

$$Q = \frac{4\pi}{\lambda} \sin\theta \quad \tan 2\theta = \frac{L_{bs}/2}{L_2}$$

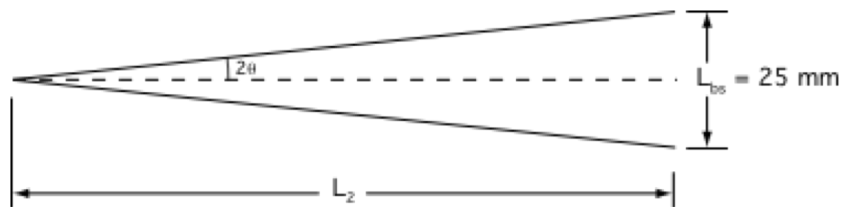
$$L_2 = \frac{\pi}{\lambda} \frac{L_{bs}}{Q}$$

Measuring Larger Structures

Exercise

Based on what you have learned, how can we design or configure a SANS instrument to measure larger objects?

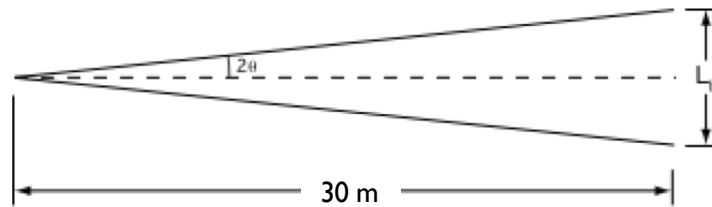
(A) Increase Distance at a given Beam Size



Calculate the required L_2 to reach $Q = 3 \times 10^{-5} \text{ \AA}^{-1}$ using neutrons with a wavelength of 4 \AA

$$L_2 = 654 \text{ m}$$

(B) Decrease Beam Size at a given Distance



Calculate the required L_{bs} to reach $Q = 1 \times 10^{-5} \text{ \AA}^{-1}$ using neutrons with a wavelength of 4 \AA .

Assuming $L_1 = L_2$, what aperture sizes would you need to obtain this L_{bs} value?

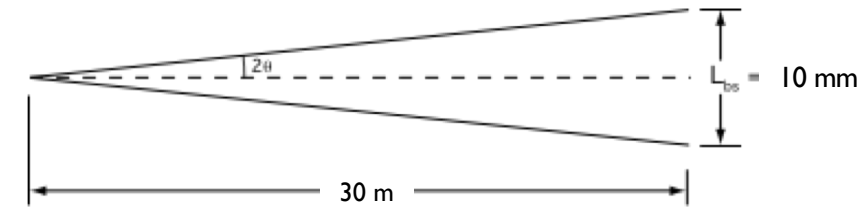
$$L_{bs} = 3.8 \text{ mm}$$

$$D_1 = 1.9 \text{ mm}$$

$$D_2 = 0.95 \text{ mm}$$

Assuming 'matched' collimation

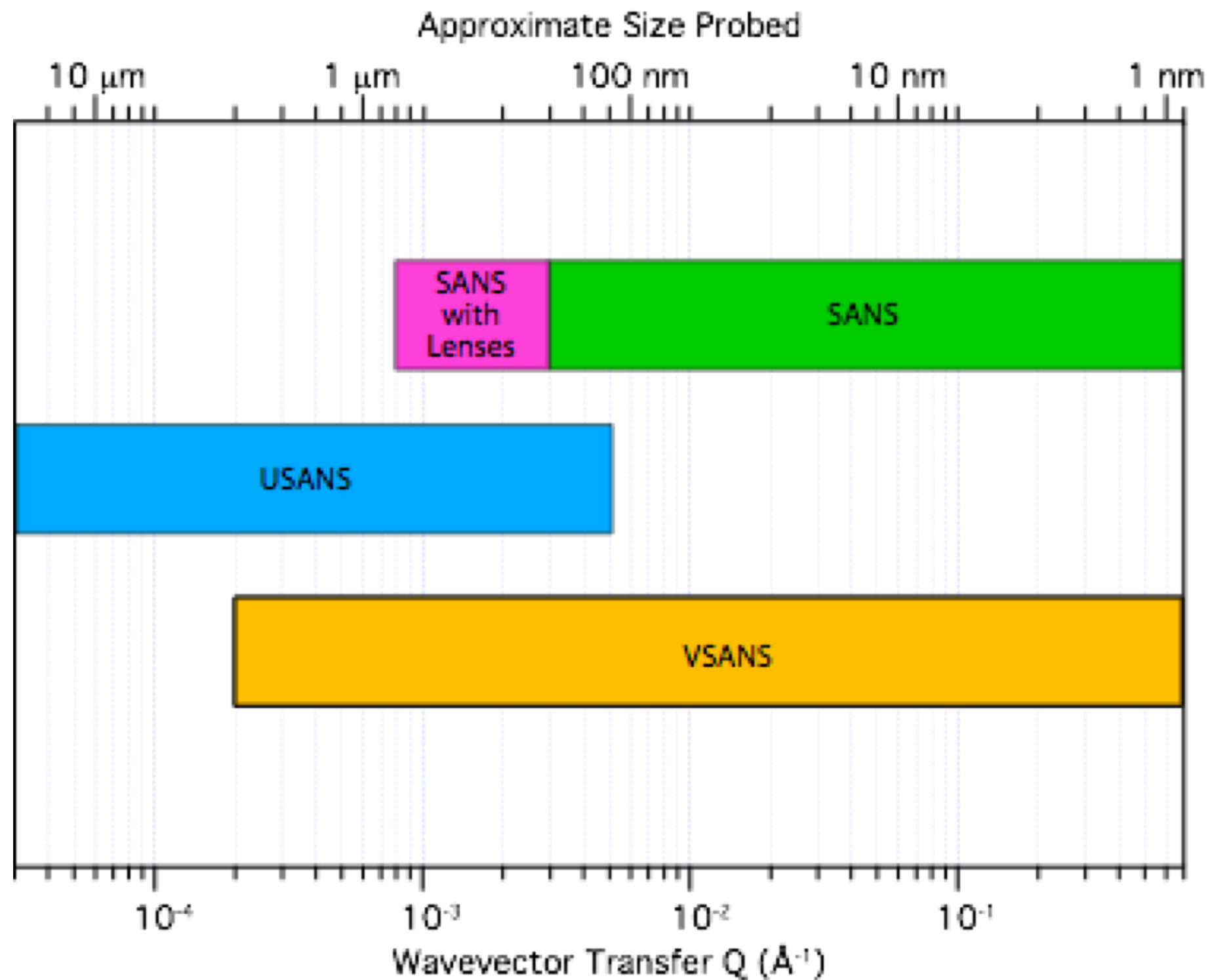
(C) Increase Wavelength at a given Beam Size and Distance



Calculate the minimum Q accessible using neutrons with a wavelength of 20 \AA .

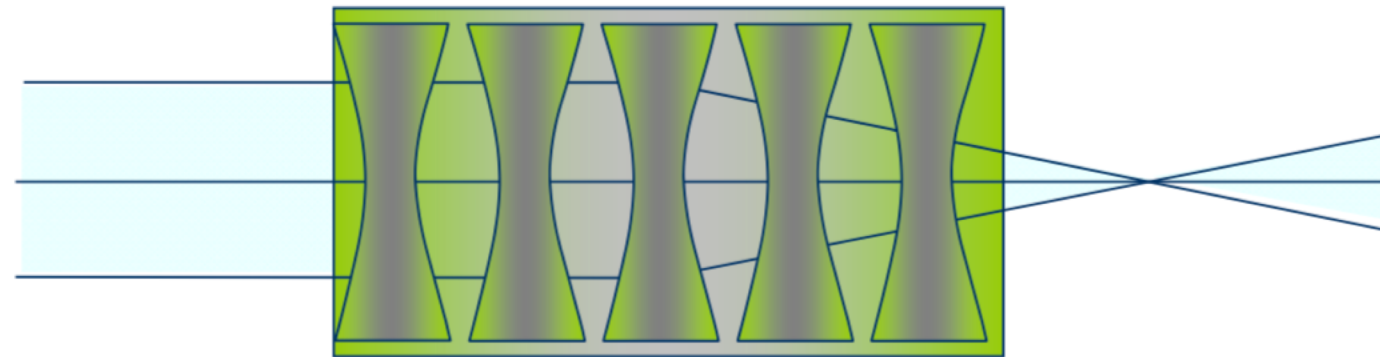
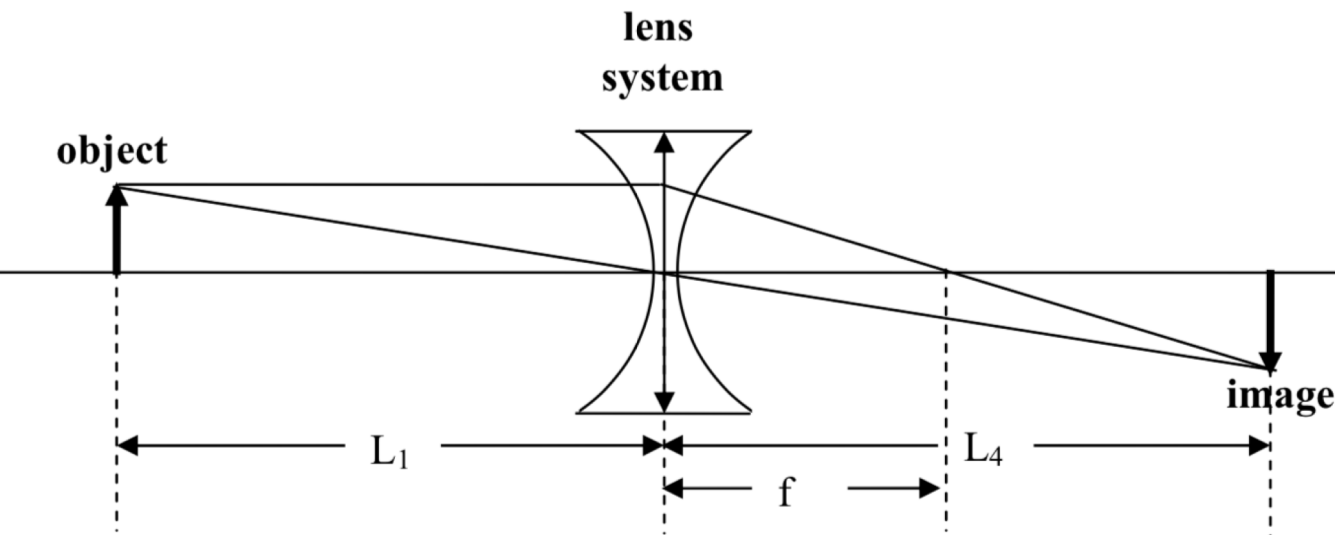
$$Q = 5.2 \times 10^{-5} \text{ \AA}^{-1}$$

Getting to Lower Q



How to get to lower Q?

Neutron Focusing Lenses



Focal length of a series of N lenses is given by:

$$f = \frac{R}{2N(1-n)} \quad n = 1 - \frac{\rho b}{2\pi} \lambda^2$$

$$\frac{1}{f} = \frac{1}{L_1} + \frac{1}{L_4}$$

$$\frac{\pi}{\rho b_c} \frac{R}{N\lambda^2} = \frac{L_1 L_4}{L_1 + L_4}$$

In the case of Magnesium Fluoride, MgF_2 :

$$\rho b / \pi = 1.632 * 10^{-6} \text{ \AA}^{-2}$$

$$n = 1 - 0.816 * 10^{-6} \lambda^2$$

Example

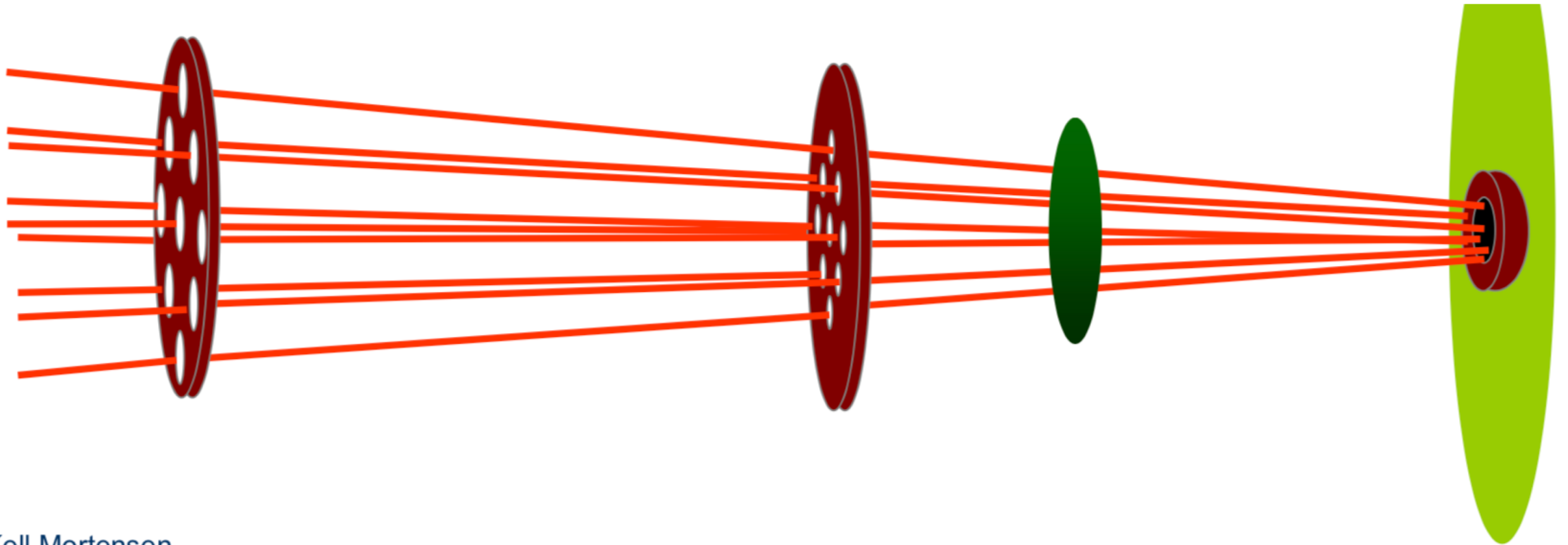
We want to focus 8 Å neutrons using MgF_2 lenses with radius of curvature $R = 2.5$ cm and with an instrument where $L_1 = 15$ m and $L_4 = 12$ m. How many lenses will we need and where do we need to put them?

$$f = \frac{L_1 L_4}{L_1 + L_4} = 6.67 \text{ m}$$

$$N = \frac{R}{2f(1-n)} = 36$$

How to get to lower Q?

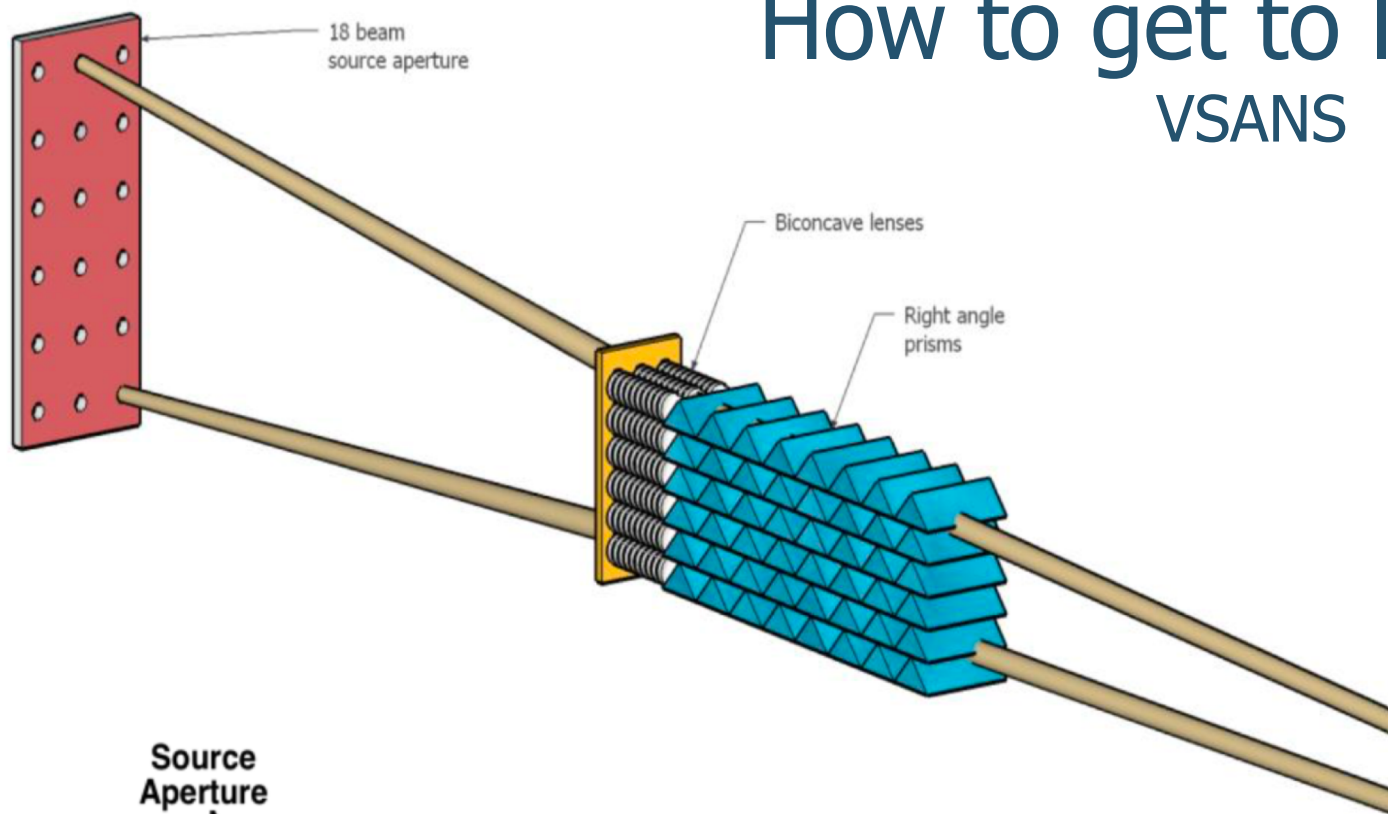
VSANS



Kell Mortensen

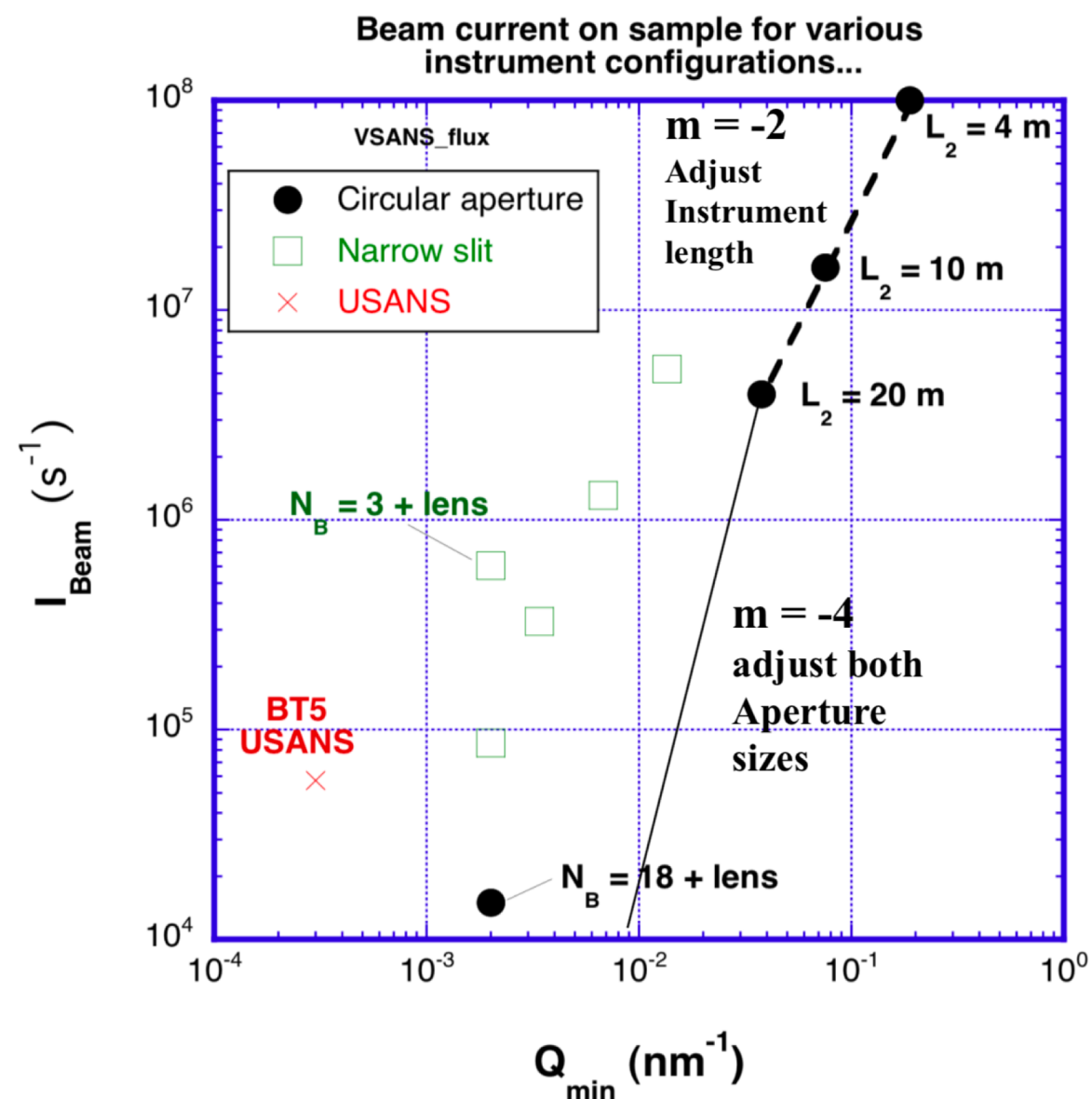
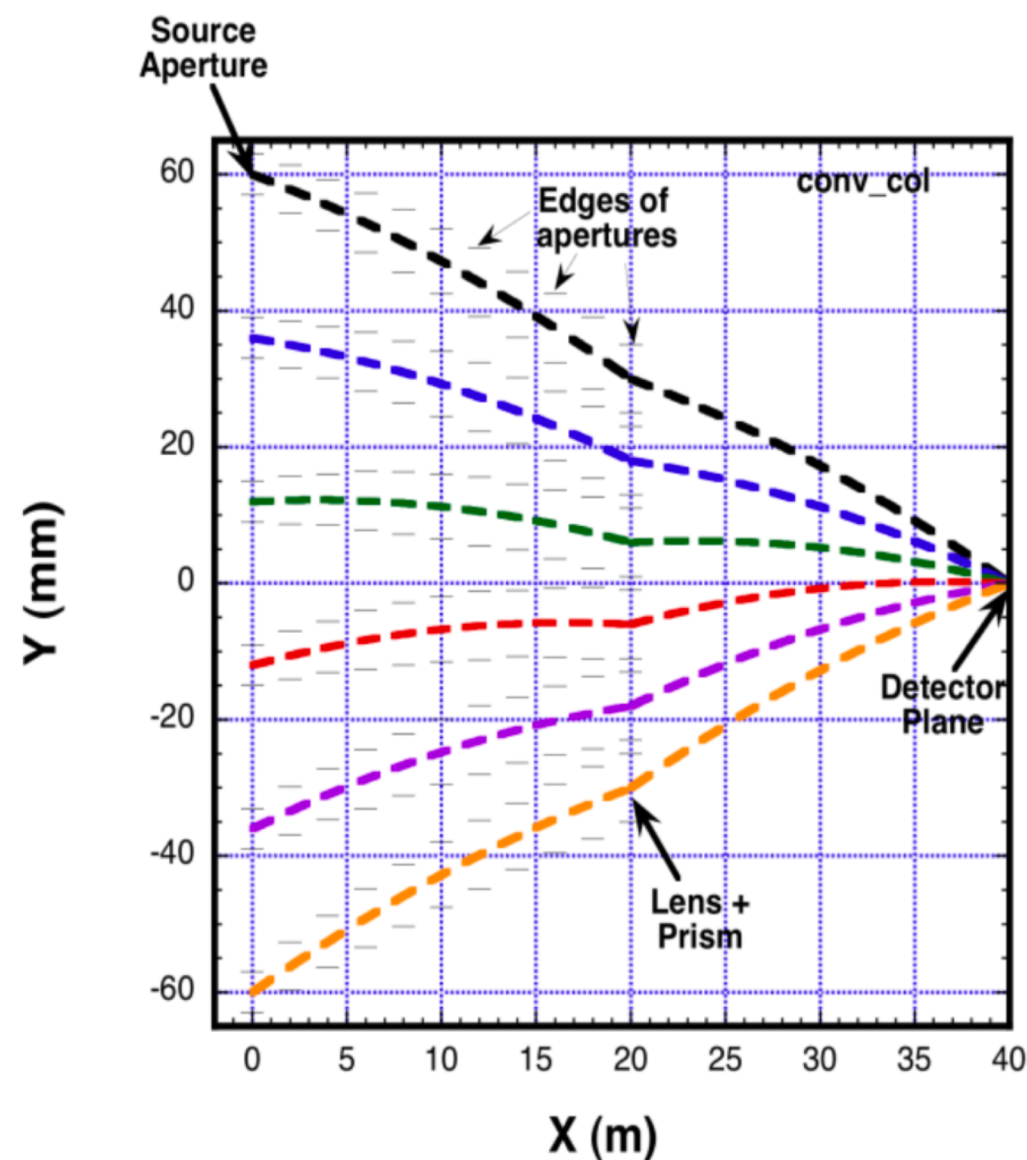
How to get to lower Q?

VSANS



NG3 VSANS @ NCNR

Started operation this year (2018)!



How to get to lower Q?

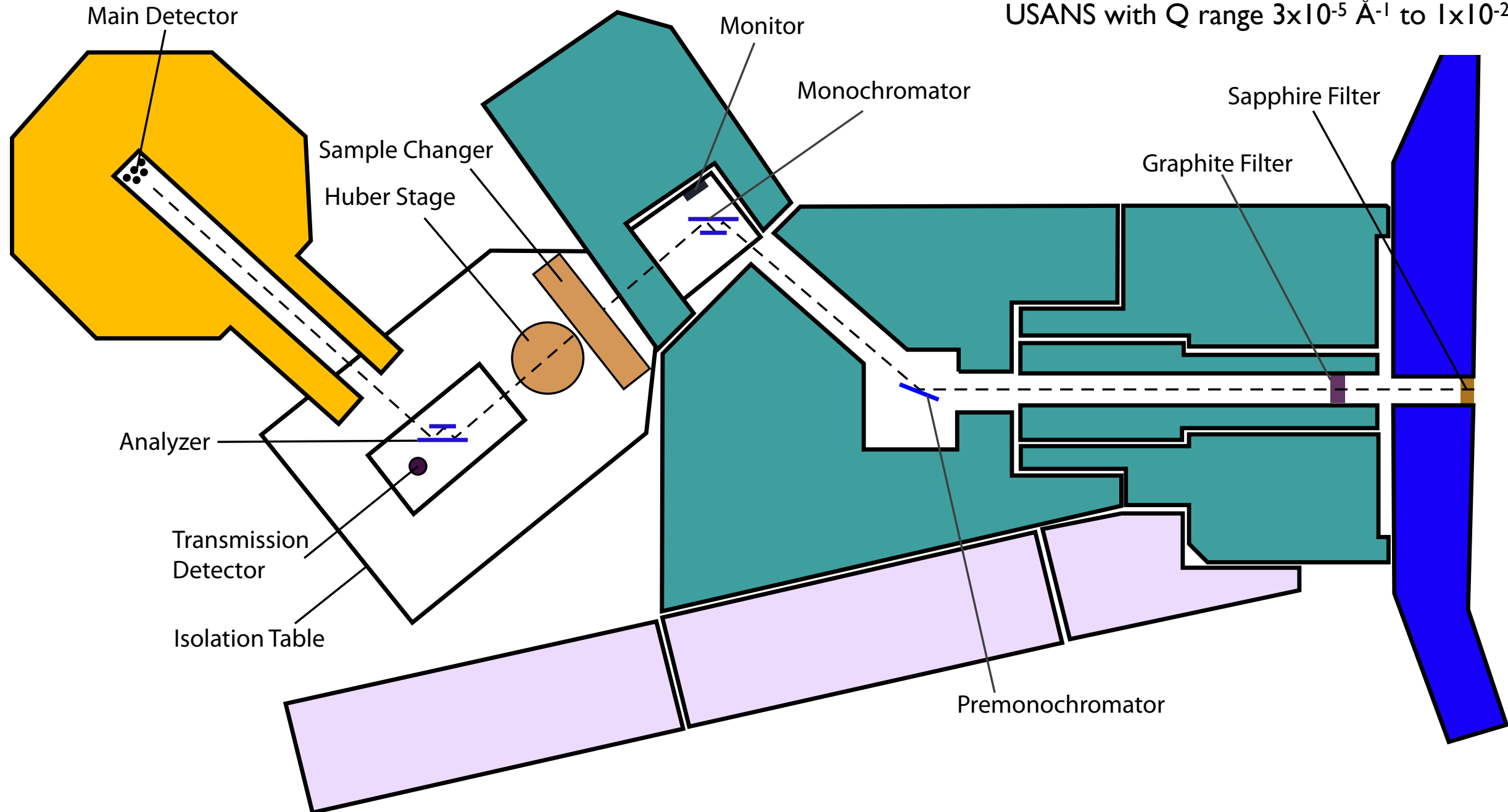
USANS

USANS Instrument BT-5

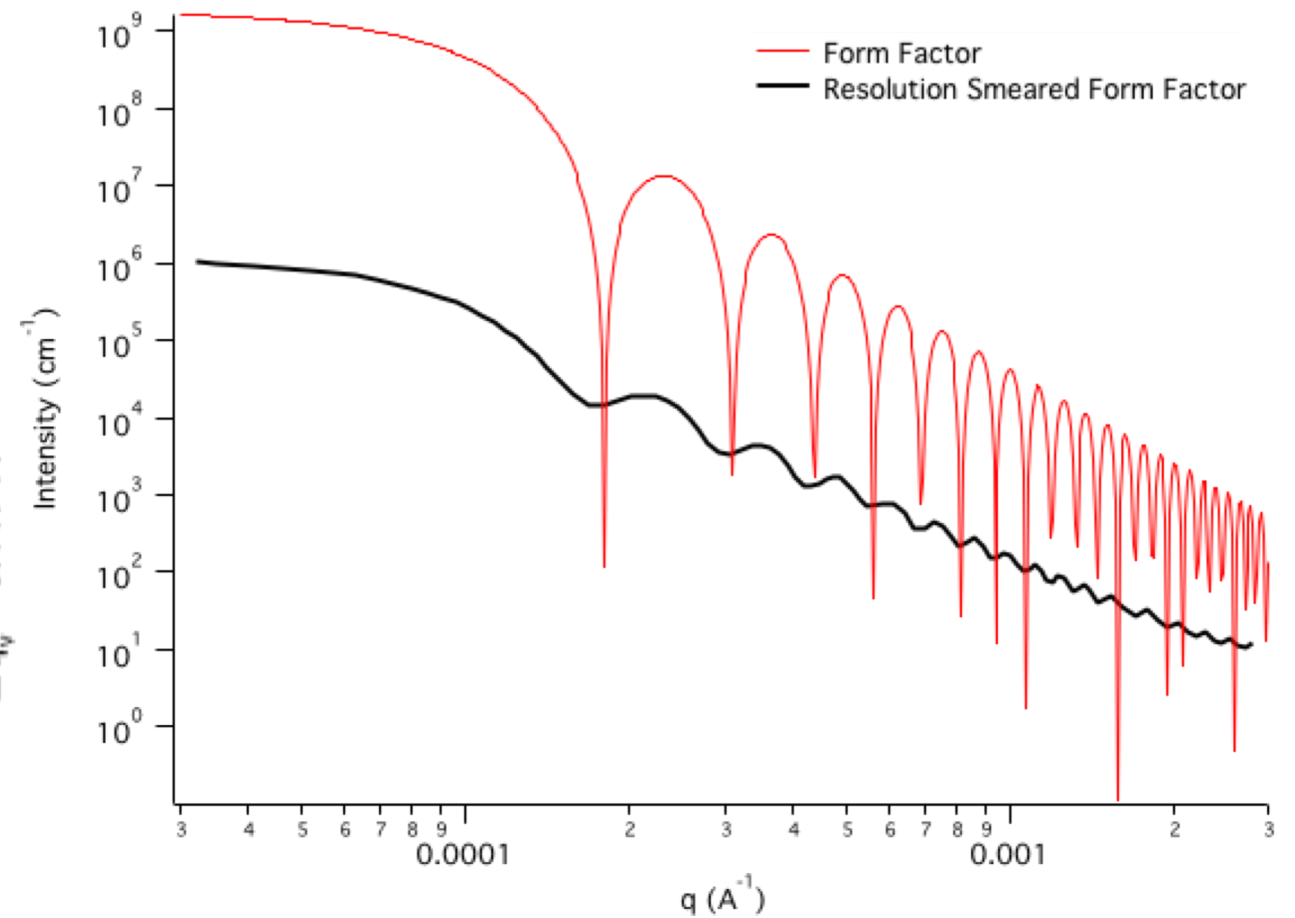
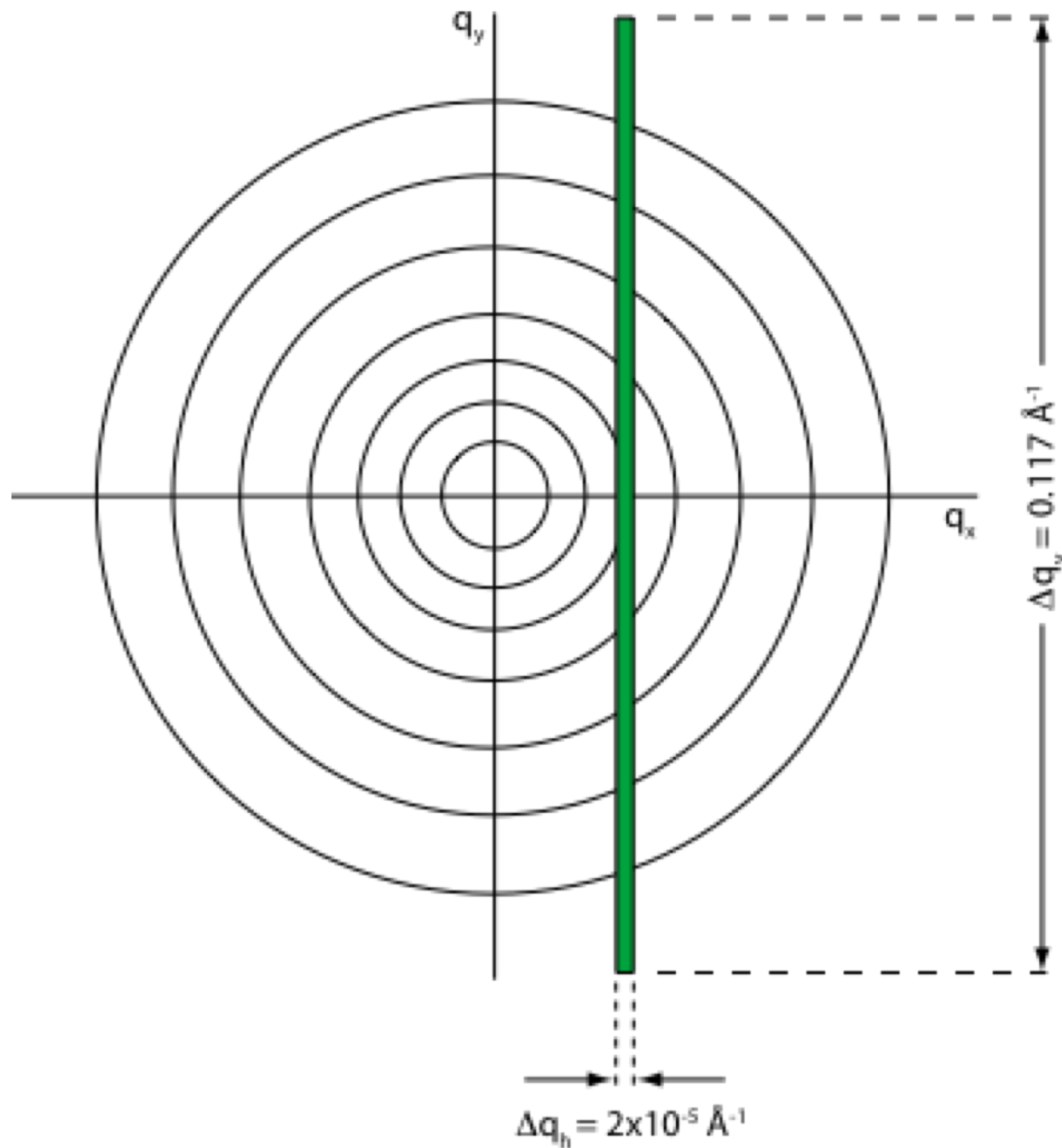
at

NIST Center for Neutron Research (NCNR)

USANS with Q range $3 \times 10^{-5} \text{ \AA}^{-1}$ to $1 \times 10^{-2} \text{ \AA}^{-1}$



Slit Geometry Resolution



$$\frac{d\Sigma_s}{d\Omega}(q) = \frac{1}{\Delta q_v} \int_0^{\Delta q_v} \frac{d\Sigma}{d\Omega}(\sqrt{q^2 + u^2}) du$$

B) Measuring Surface Structures

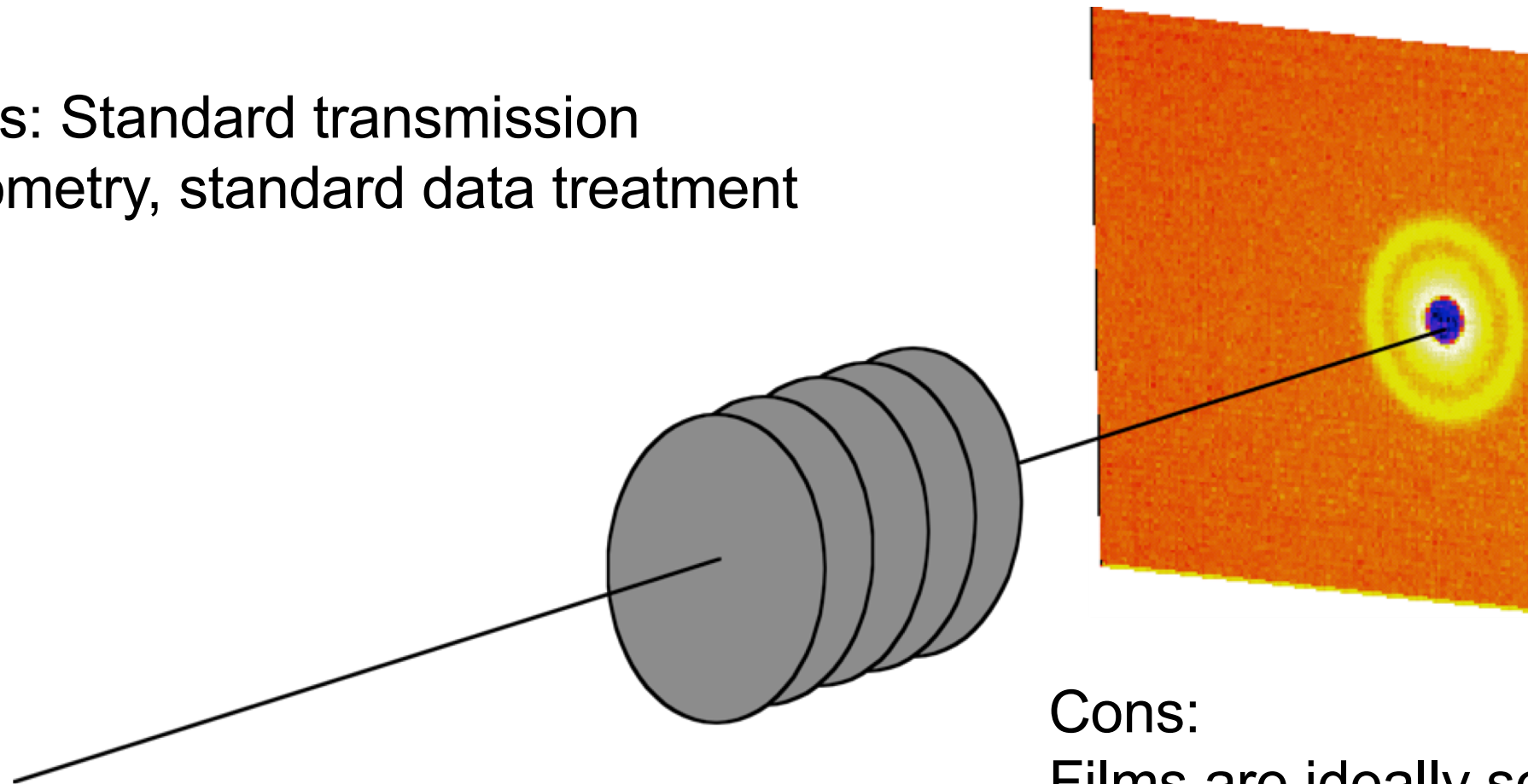
In Plane Structure at Surfaces

- SANS provides information about bulk structure in-plane (to several mm depth)
- Reflectometry provides information about structure perpendicular to interface (to a few hundred nm depth)

Transmission SANS

Stack of wafers coated with thin film...

Pros: Standard transmission geometry, standard data treatment



Cons:

Films are ideally several microns - not really looking at near surface region

May need many wafers - background from substrate

Reflectometry

Specular reflectivity (Q_z) probes the vertical structure with Å-resolution

Off-specular reflectivity (Q_x) probes μm -structures in the direction of the beam.

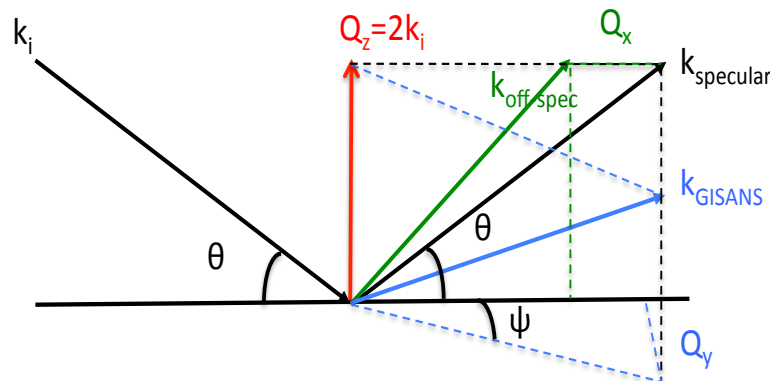
(limited by neutron coherence length)

specular reflectivity

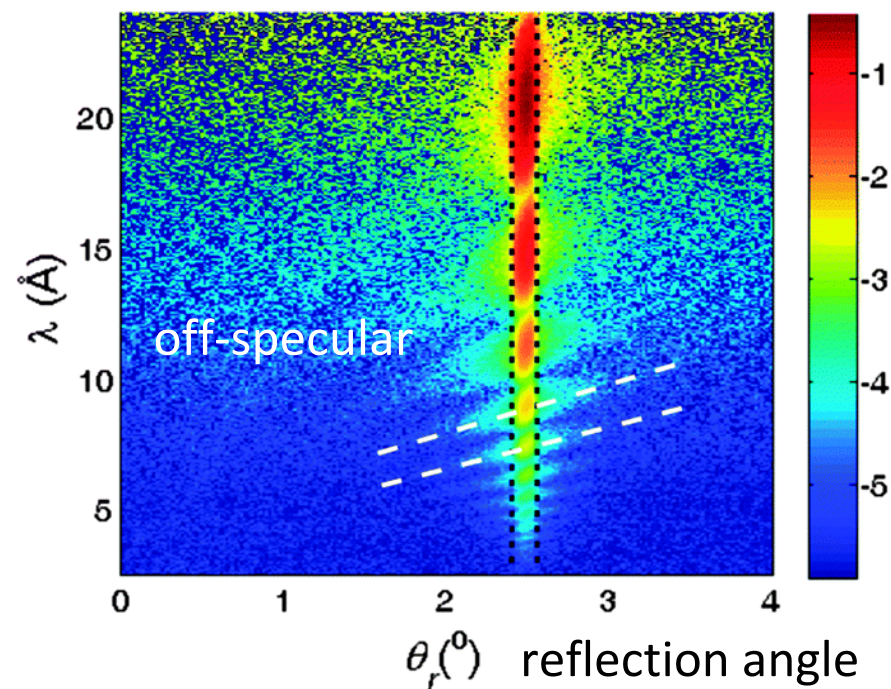
$$Q_y = 2\pi(\sin\psi + \cos\theta) / \lambda$$

$$Q_x = 2\pi(\cos\psi\cos\theta - \cos\theta) / \lambda$$

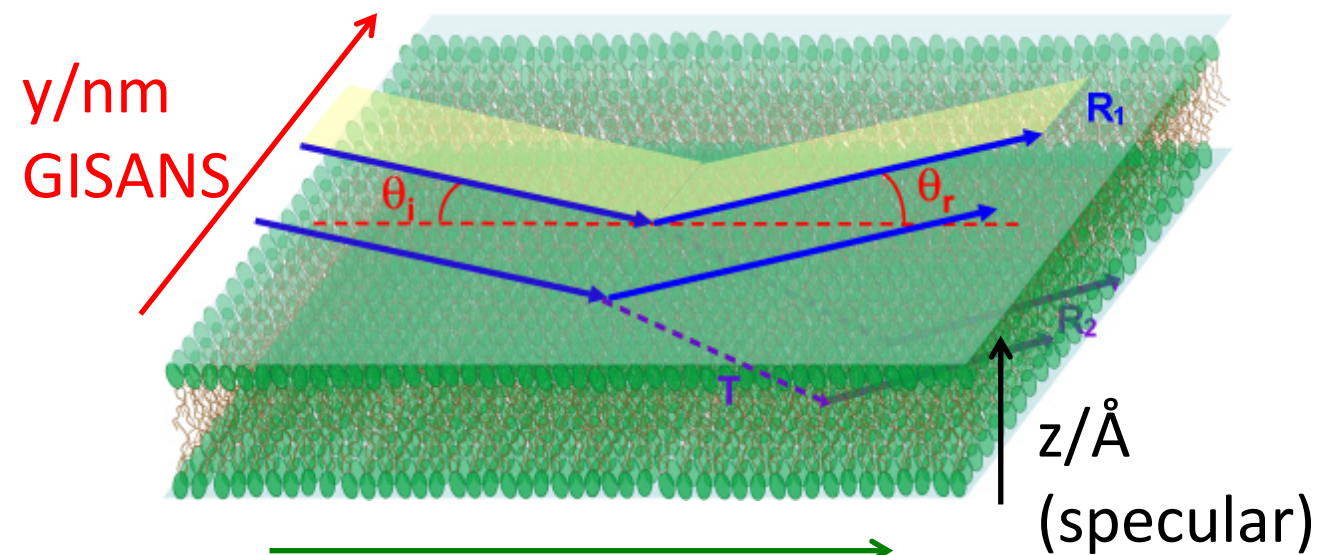
$$Q_z = 4\pi\sin\theta / \lambda$$



specular $\theta_r = \theta_i$



Reflectivity (specular and off-specular) is measured with a divergent wide beam (cm) – this averages lateral structure in y -direction



$x/\mu\text{m}$ (off-specular)
e.g. thickness fluctuations, stripes, domains

Grazing Incidence SANS

“True” GISANS

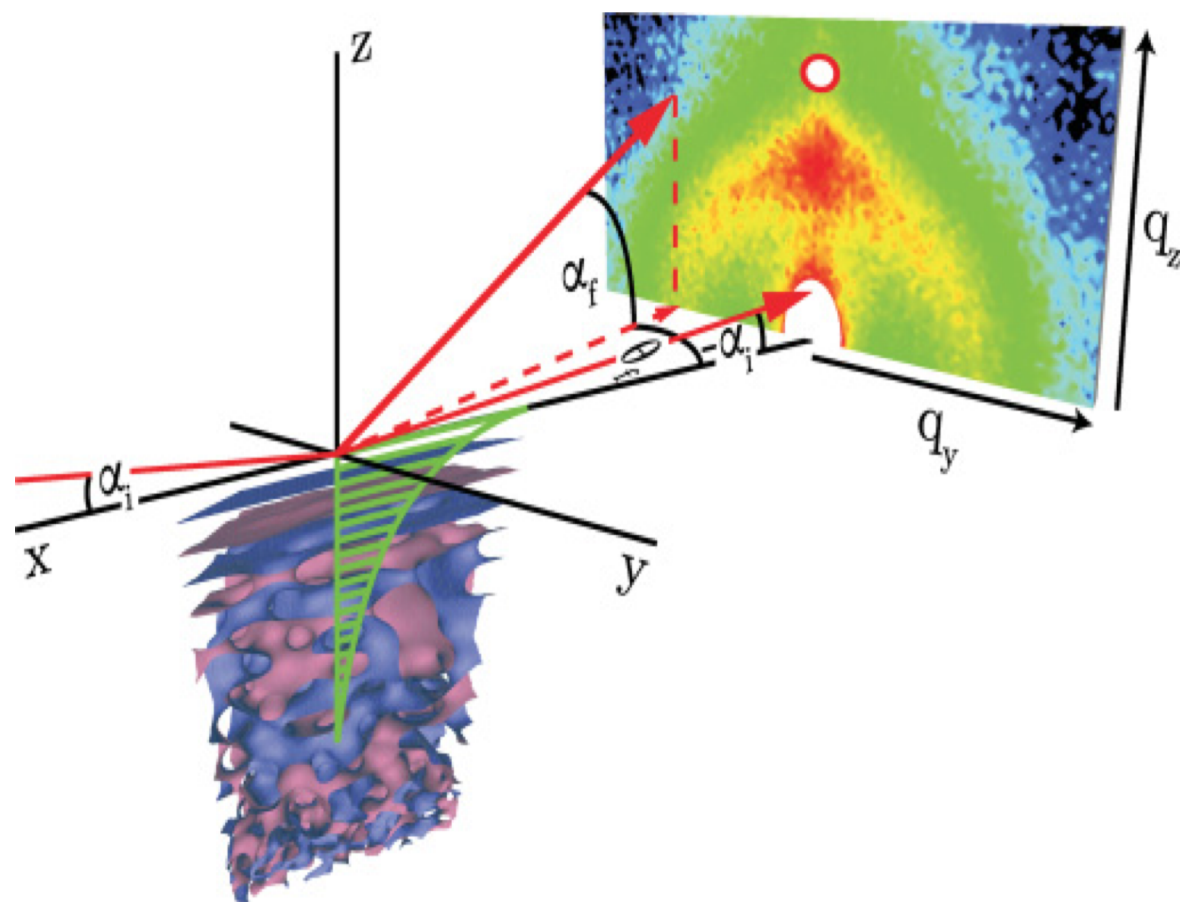
- Incoming neutrons at angle to interface smaller than the critical angle.
- Evanescent wave scattering from interfacial region with thickness determined by the wavelength of the neutrons, contrast (difference in refractive index of the two media) and the angle.
- Intensity of wave decays exponentially
- Done very successfully with x-rays - neutron intensity means that scattering by the evanescent wave is very weak.

“Near Surface” SANS

- Incoming neutrons at angle greater than the critical angle
- Refracted wave scattered from region below the interface. Scattering volume largely determined by sample environment
- Is a significant cause of background in reflectometry experiments.
- Is the bulk of what is measured as Off-Specular reflection.

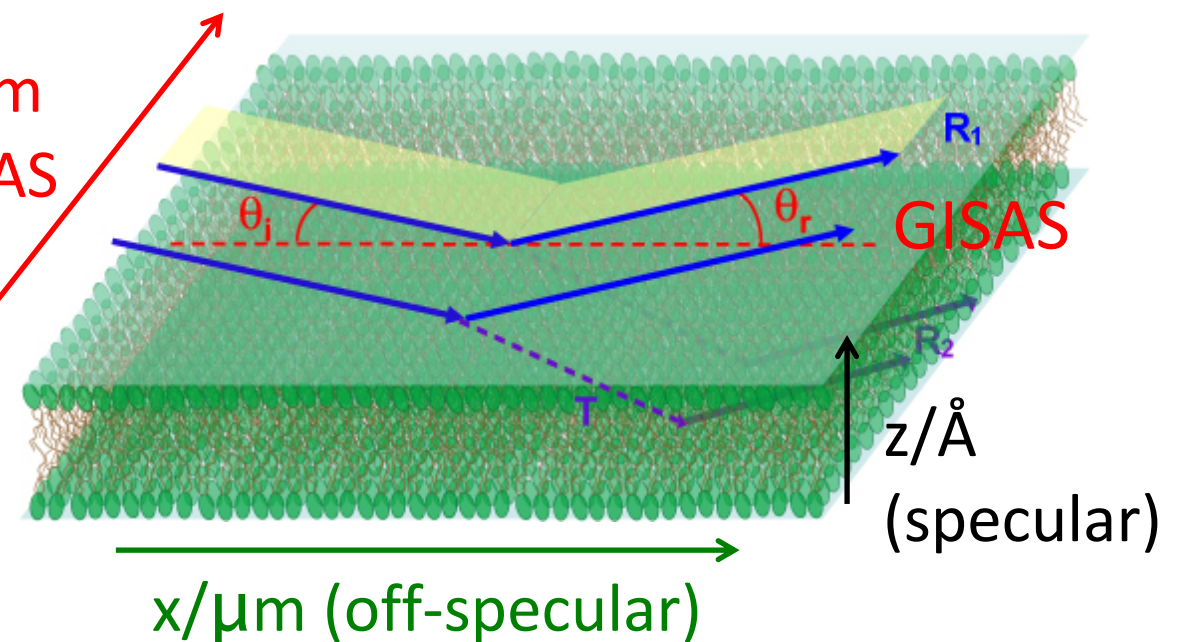
GISANS

Grazing Incidence SANS probes nm-structures in the y -direction. The difference between GISANS and neutron reflectivity measurements is the beam collimation (Q_y -resolution):



Reflectivity (specular and off-specular) is measured with a divergent wide beam (cm) – this averages lateral structure in y -direction

y/nm
GISAS

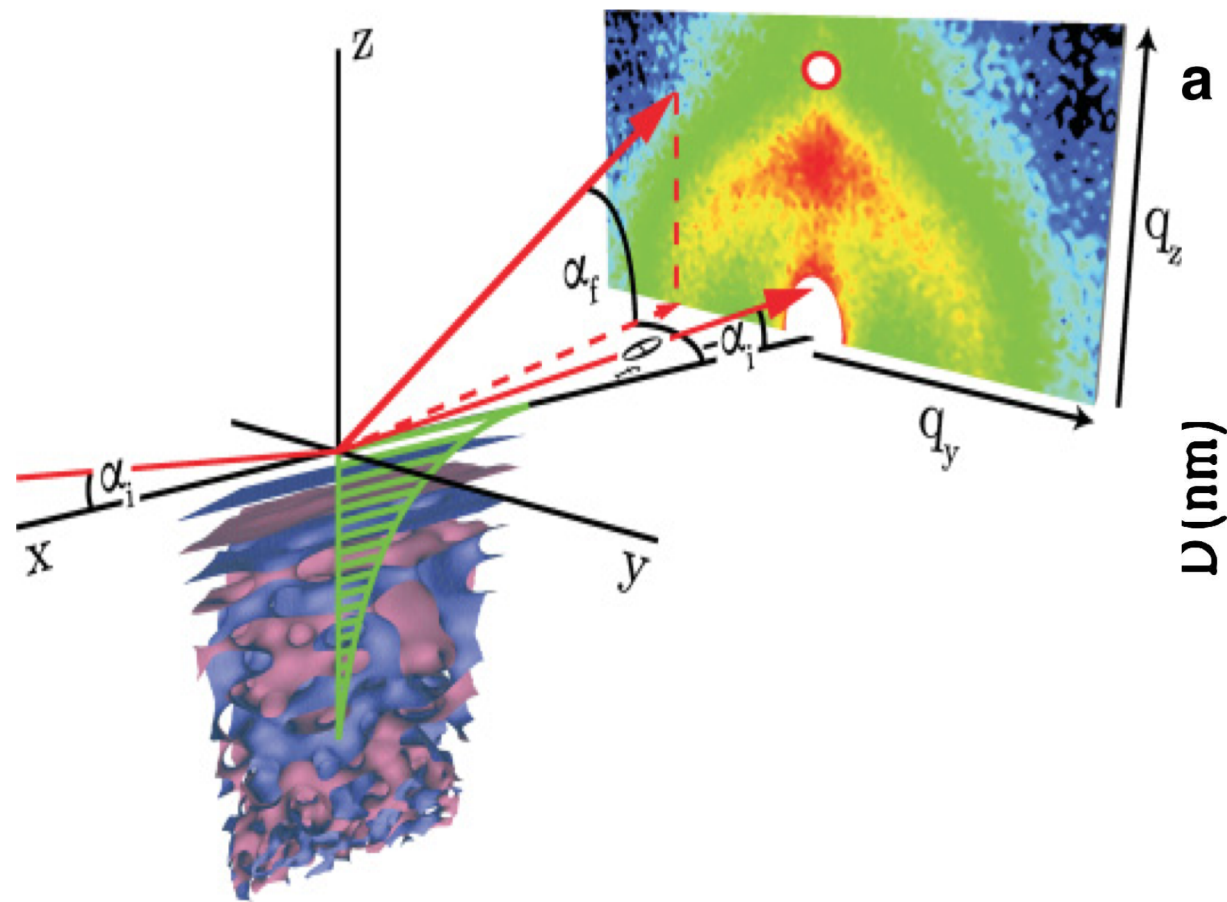


GISANS data is measured with a **narrow low-divergence beam** in the y -direction to determine the 2D structure = SANS from surface

H. Frielinghaus, M. Kerscher, O. Holderer, M. Monkenbusch, D. Richter, Phys. Rev. E, 85, (2012), 041408.

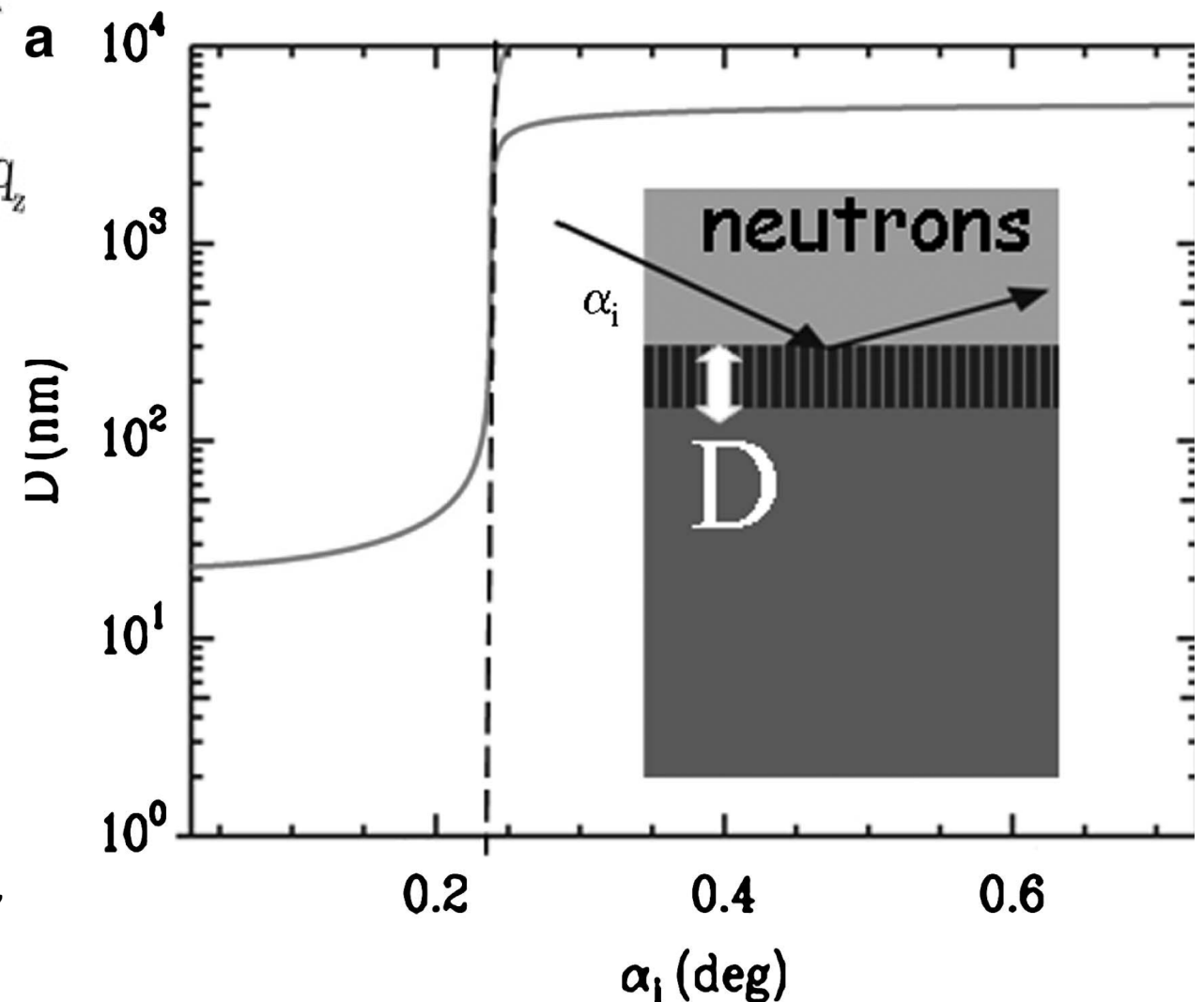
GISANS

- Grazing Incidence Small Angle Scattering (GISAS) is measured at a small reflection angle, typically 0.2-0.5 degrees:



H. Frielinghaus, M. Kerscher, O. Holderer, M. Monkenbusch, D. Richter, Phys. Rev. E, 85, (2012), 041408.

The penetration depth of neutrons is angle dependent:



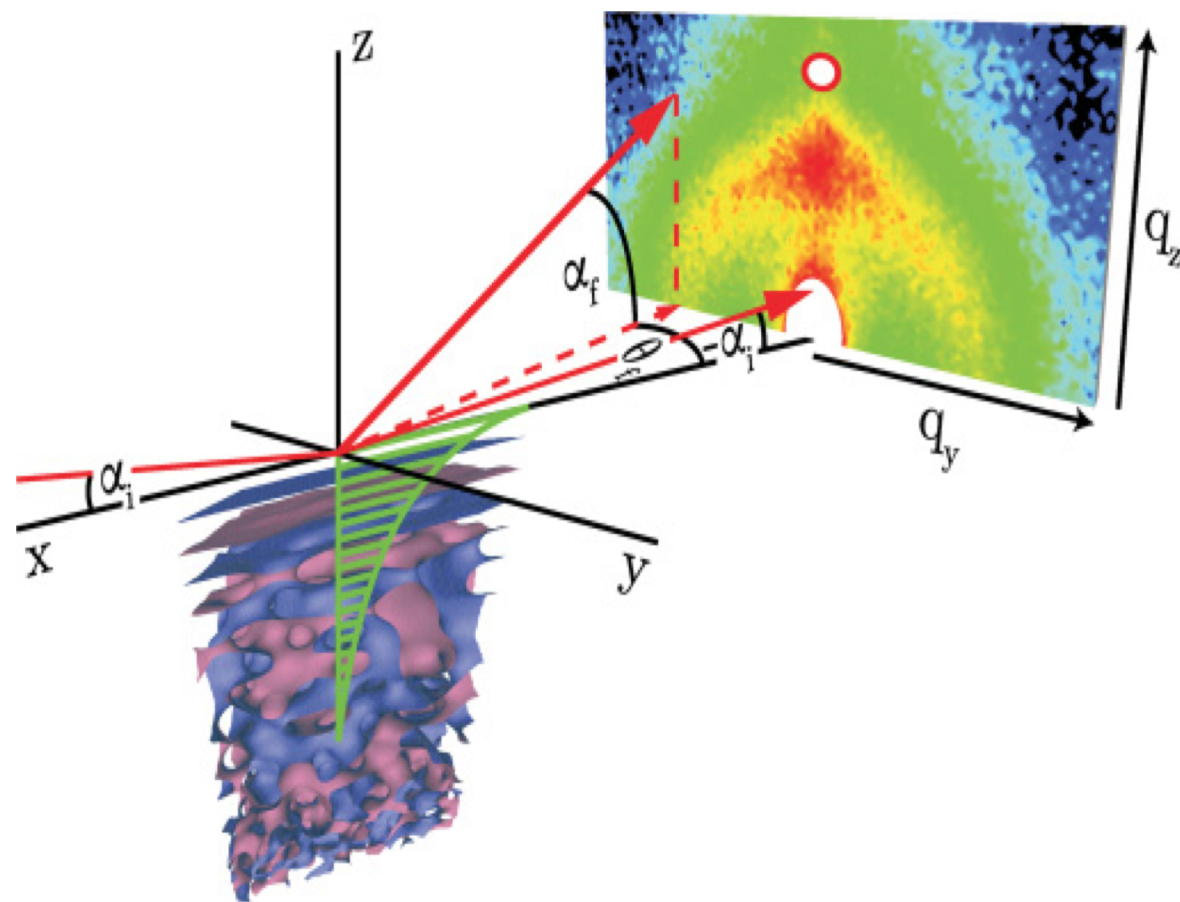
P. Mueller-Busch-Baum, Polymer Journal (2013) 45, 34–42

GISANS

Below the angle of total reflection, only an evanescent wave penetrates into the surface

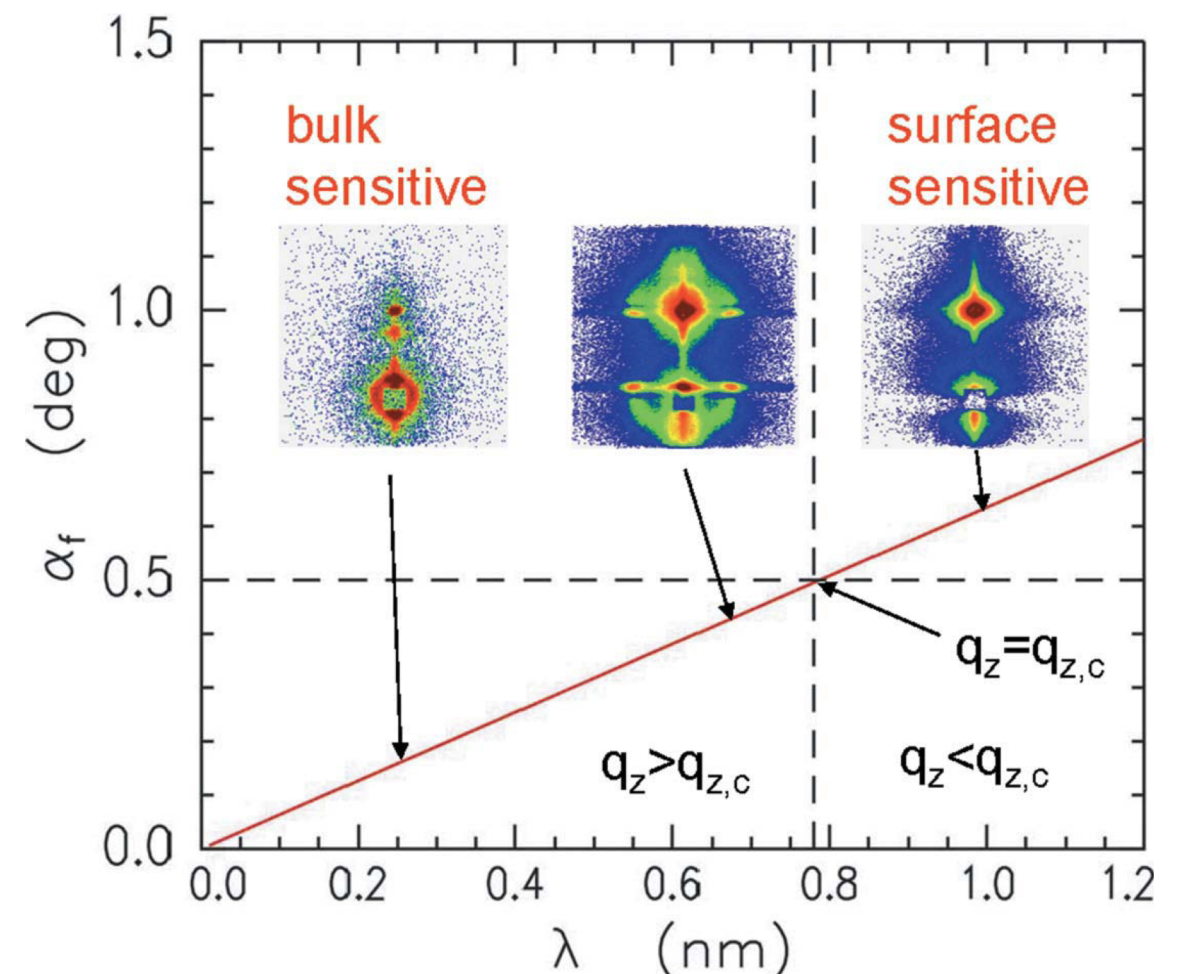
-> small angle scattering of reflected beam = surface sensitive

Below the critical wavelength, neutrons penetrate – *Near surface scattering -> bulk SANS*



H. Frielinghaus, M. Kerscher, O. Holderer, M. Monkenbusch, D. Richter, Phys. Rev. E, 85, (2012), 041408.

Surface sensitivity above critical wavelength



P. Mueller-Busch-Baum, Polymer Journal (2013) 45, 34–42

Depth Sensitive ToF GISANS

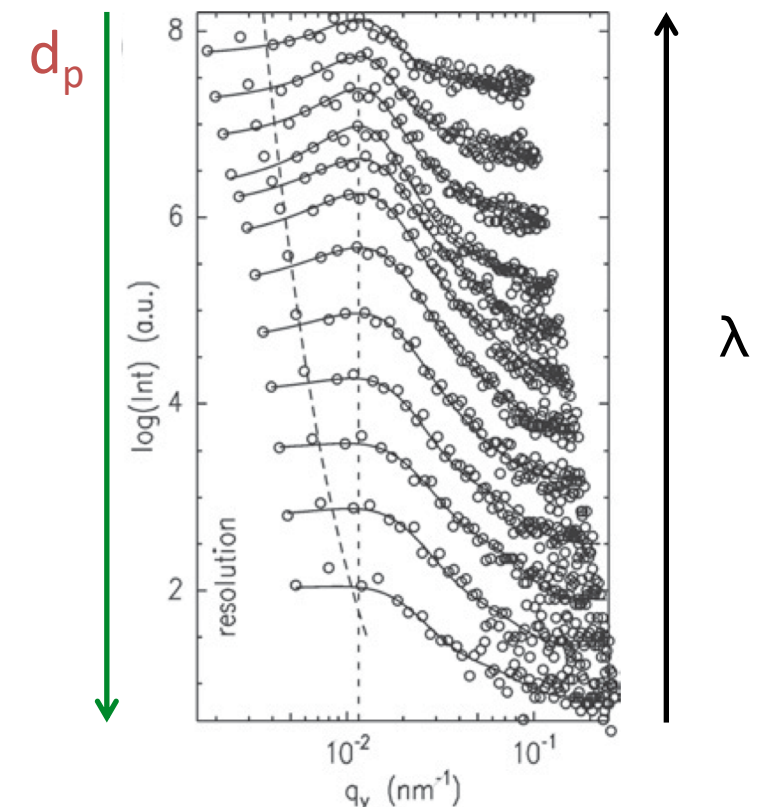
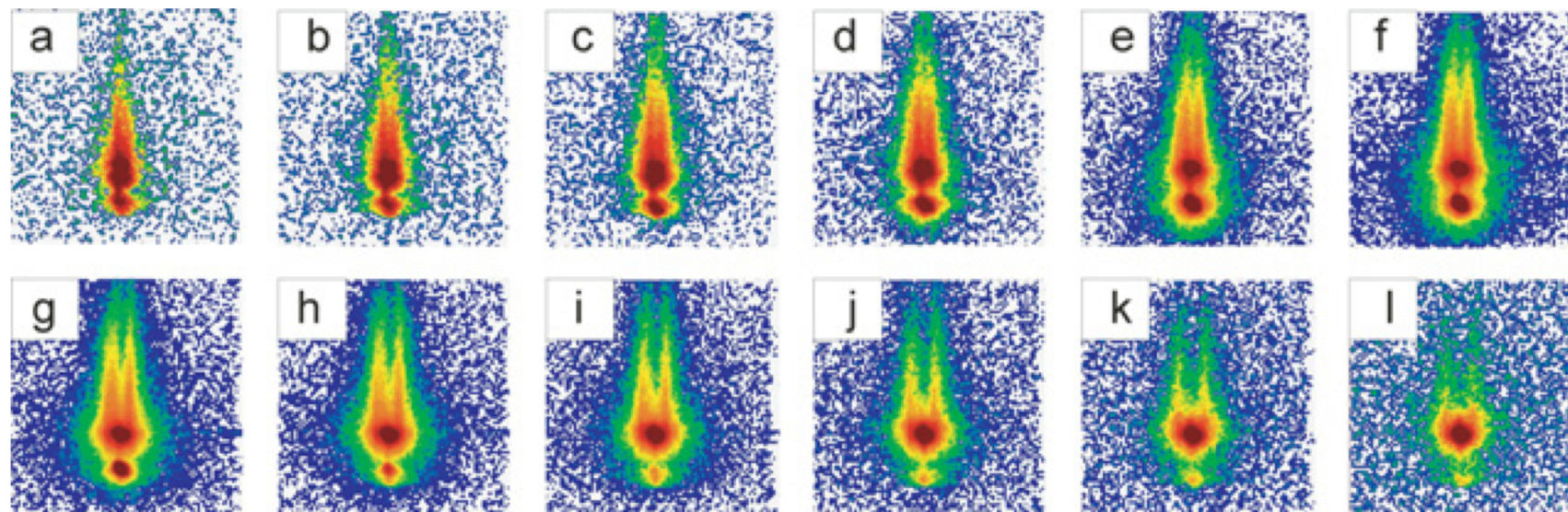
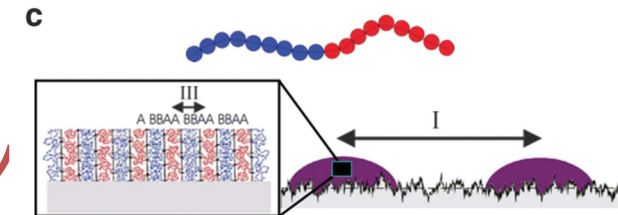
Time-of-flight GISANS using a polychromatic neutron beam:

- *probes surface structure at different depths from interface **simultaneously***

Tof- GISANS can probe the depth profile of interfaces

-> Particle size, shape, distances, chemical composition

Buried interfaces that are not accessible by AFM or EM



TOF-GISANS from a polymer nanodot film:

The corresponding mean wavelengths are a) 0.50nm, b) 0.55nm, c) 0.61nm, d) 0.68nm, e) 0.75nm, f) 0.82nm, g) 0.91nm, h) 1.00nm, i) 1.11nm, j) 1.22nm, k) 1.35nm and l) 1.48 nm.

P. Müller-Bushbaum et al. Eur. Phys. J. Special Topics 167, 107–112 (2009)

C) Measuring Time Dependent Structure

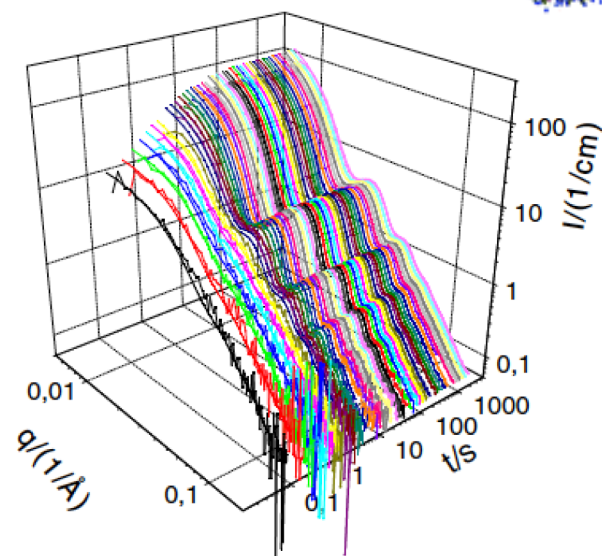
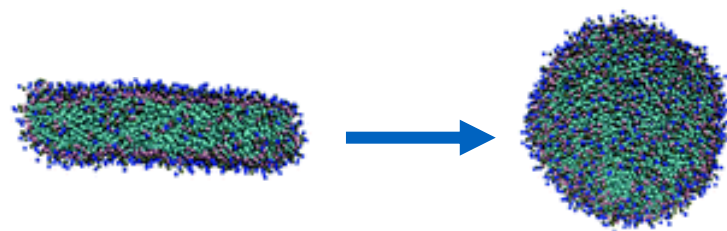
Time resolved SANS

What time scale?

If kinetics are on the second to minute time scale and scattering is reasonably strong then this can be done with sequential measurements.

If time scale is shorter or scattering is weak other approaches are needed

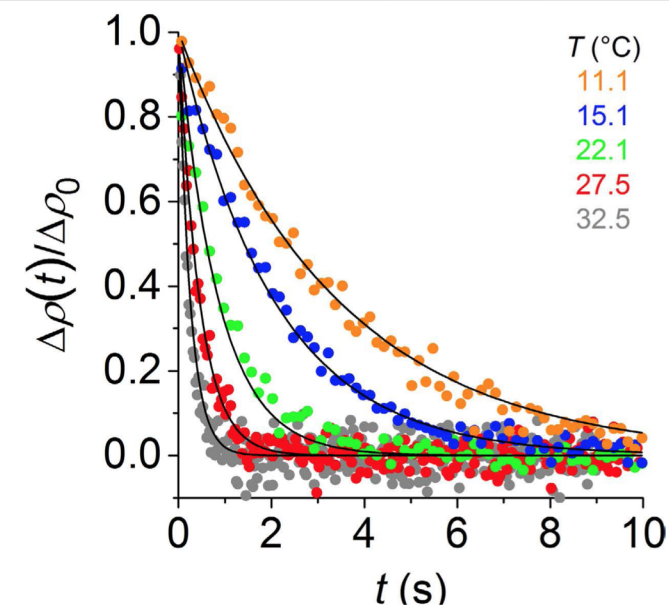
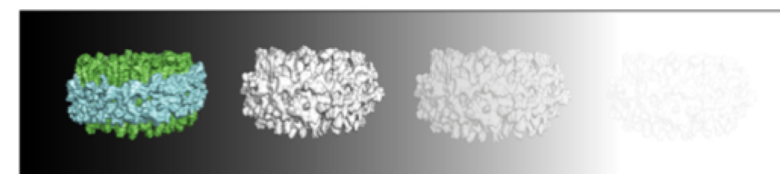
Surfactant disc to vesicle transition



50-100ms shots repeated 10-25 times

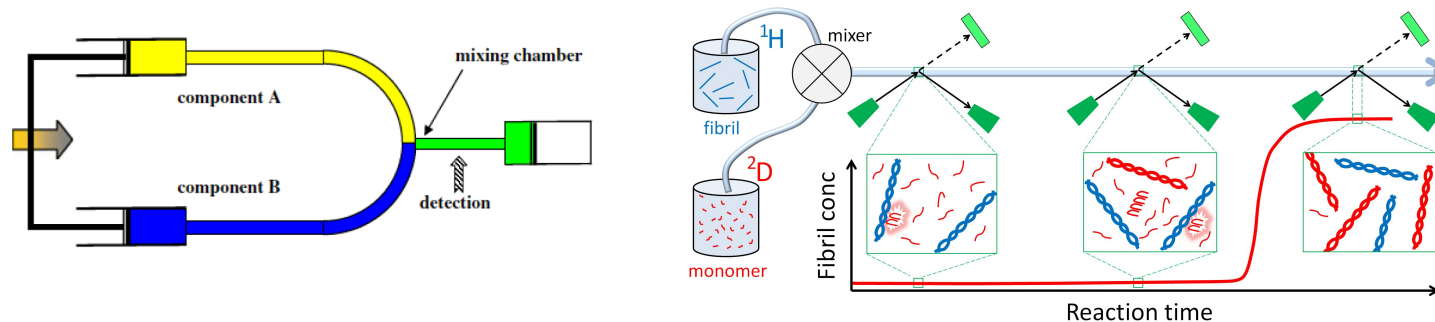
Bressel et al., Colloid Polym Sci (2010) 288:827–840

Lipid transfer between nanodiscs



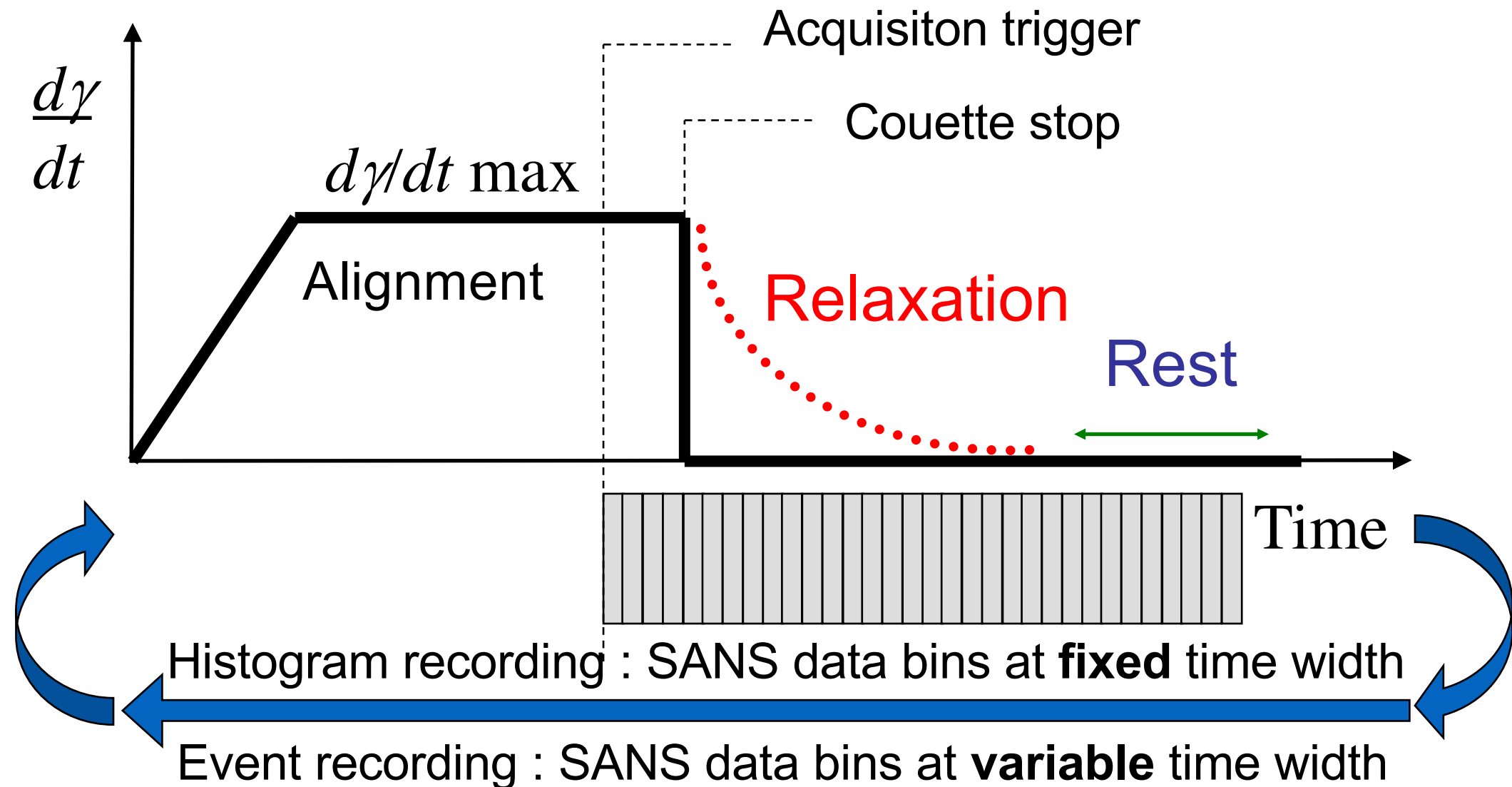
Cuevas Arenas et al., Scientific Reports 7, 45875-1-45875-8 (2017)

... such as making use of sample environment to capture time axis using stopped-flow and flow-through mixing.



Second to sub-second kinetics

Timeslicing



Relies on reversibility of response to stimulus

Limited by wavelength band due to range of time of flight

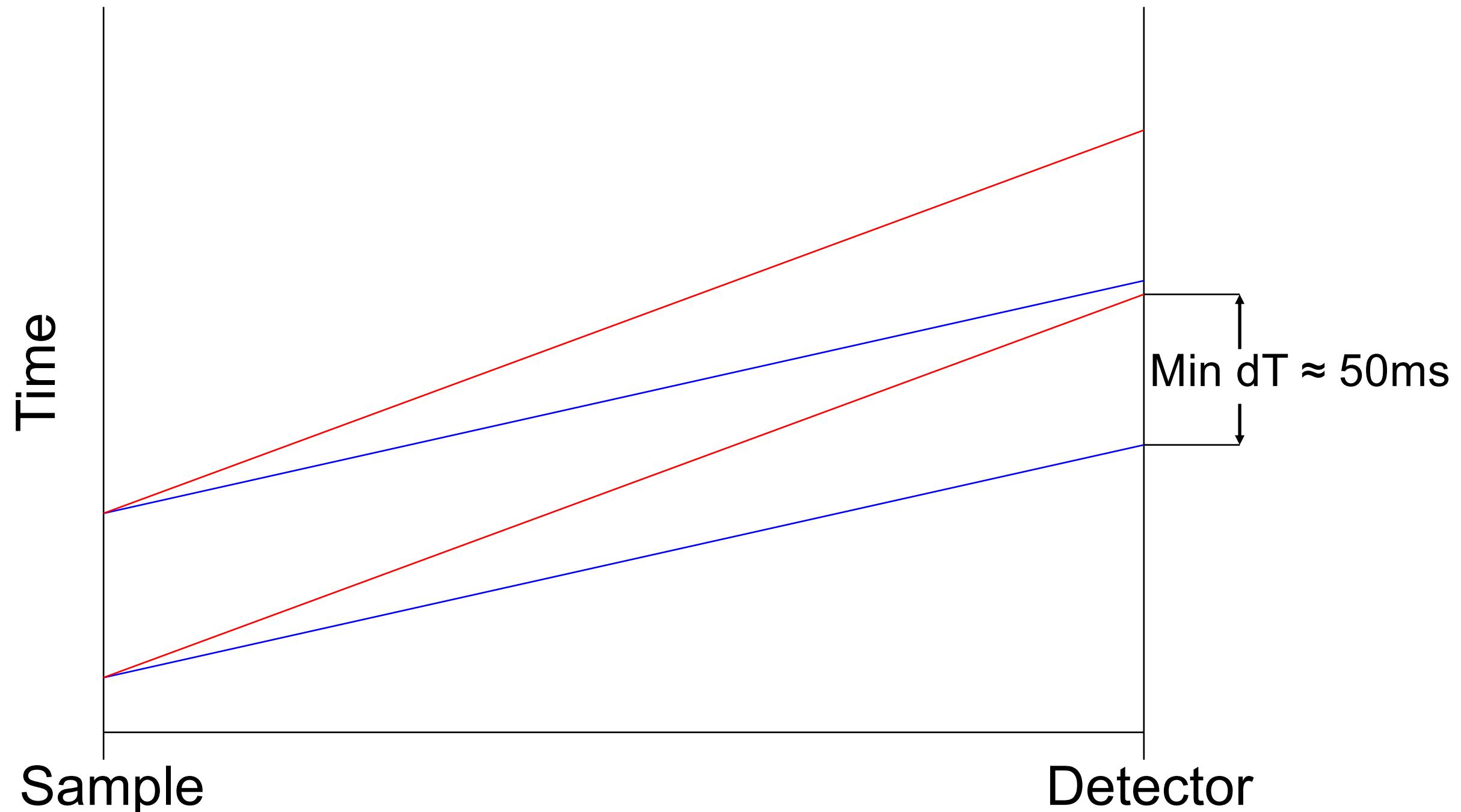
"Relaxation of a shear-induced lamellar phase measured with time resolved small angle neutron scattering",
L. Porcar, W.A. Hamilton, P.D. Butler and G.G. Warr, *Physica B: Condens. Matter.* 350 E963 (2004).

"Fast Relaxation of a Hexagonal Poiseuille Shear-induced Near-Surface Phase in a Threadlike Micellar Solution",
W.A. Hamilton, P.D. Butler, L.J. Magid, Z. Han and T.M. Slaweki, *Physical Review E (Rapid Communications)* **60**, 1146 (1999)

Second to sub-second kinetics

Continuous Source Timeslicing

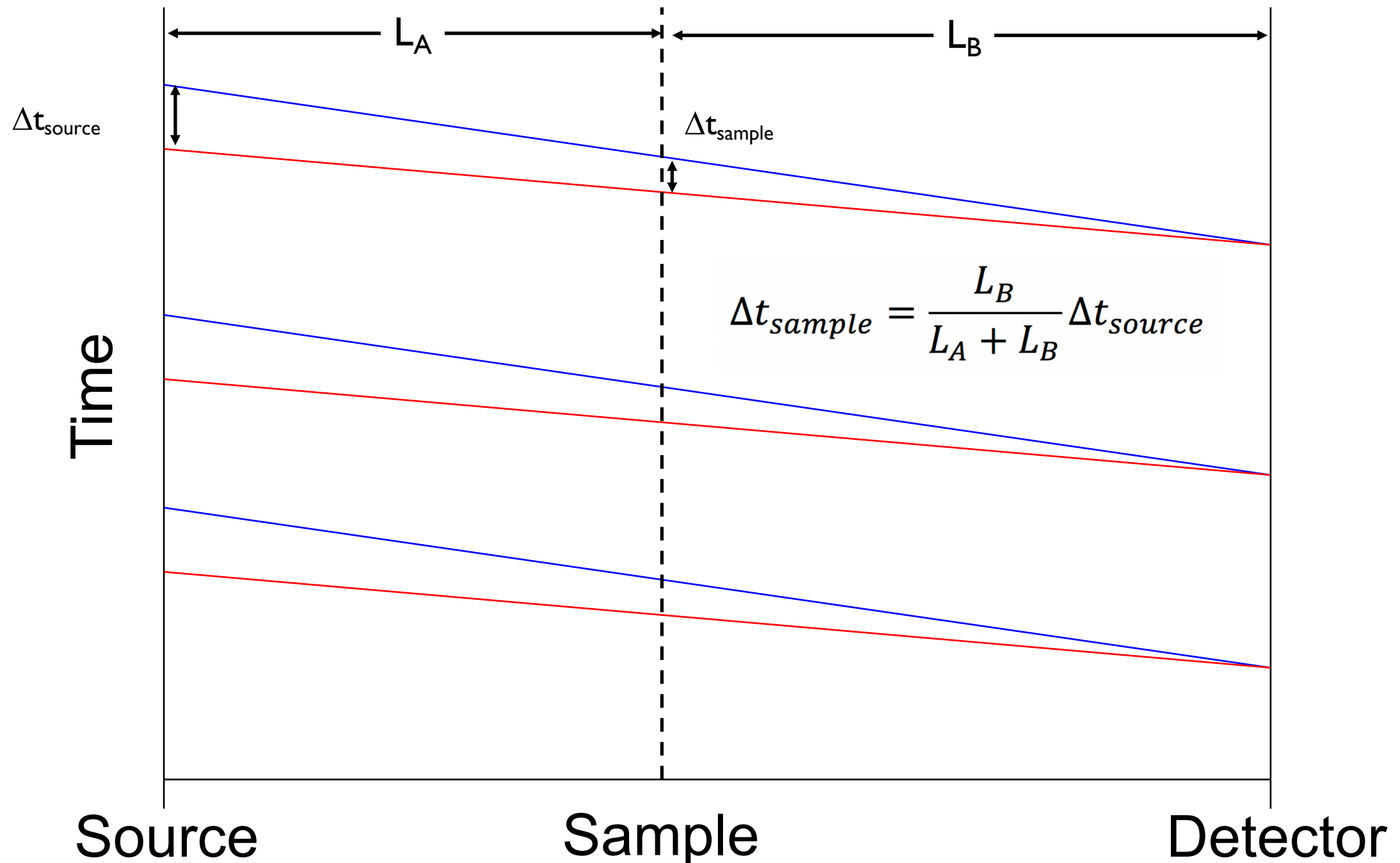
Minimum timescale limited by wavelength band due to range of time of flight



Second to sub-second kinetics

Time-of-flight Source Timeslicing

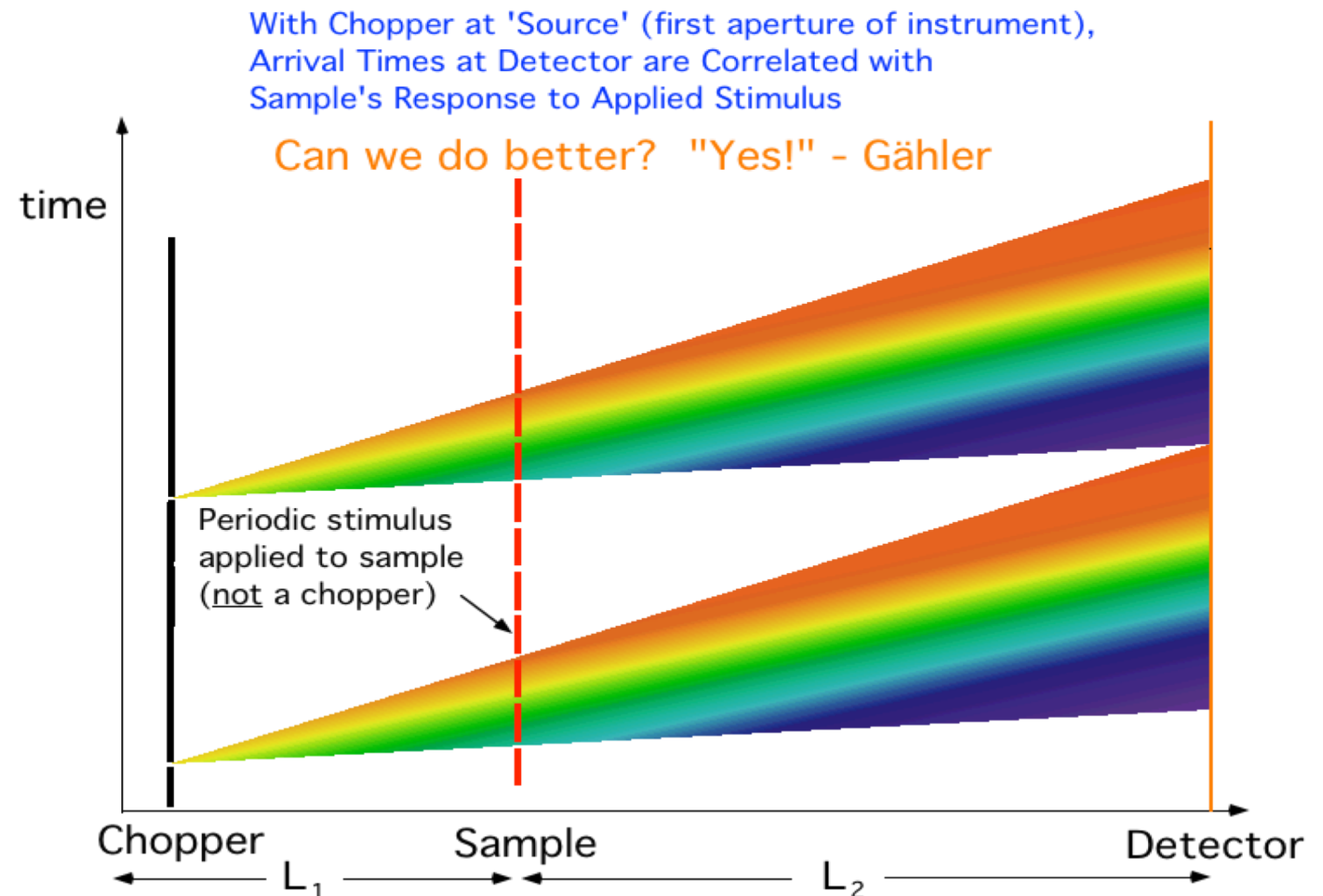
Minimum timescale limited by wavelength band due to range of time of flight



Sub-millisecond timescales?

TISANE (R Gähler, ILL)

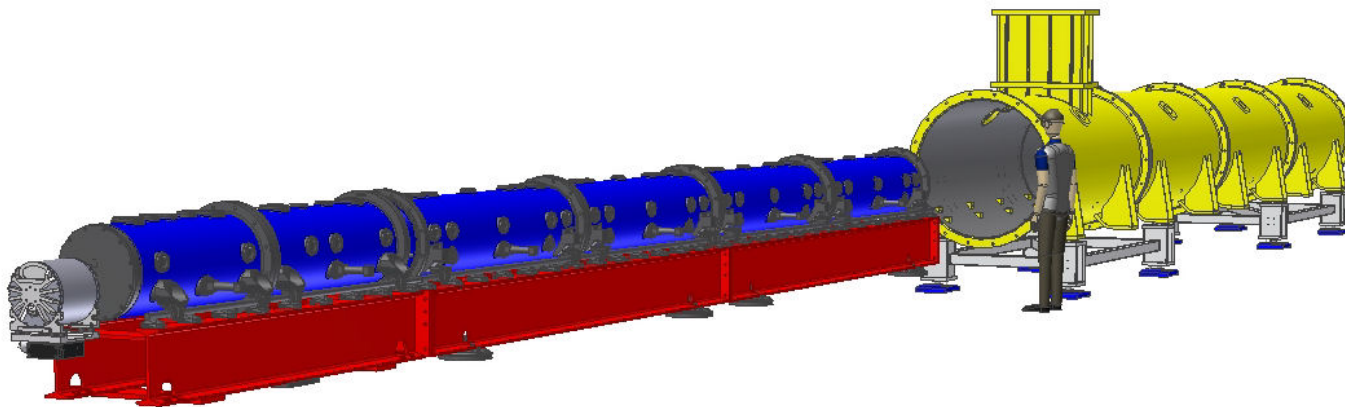
- Chopper at source
- Sample stimulus rate and chopper synchronized
- Neutrons that arrive at the same time were scattered at the same time in the sample response curve
- Can get $50\mu\text{s}$ - 100ms time resolution.



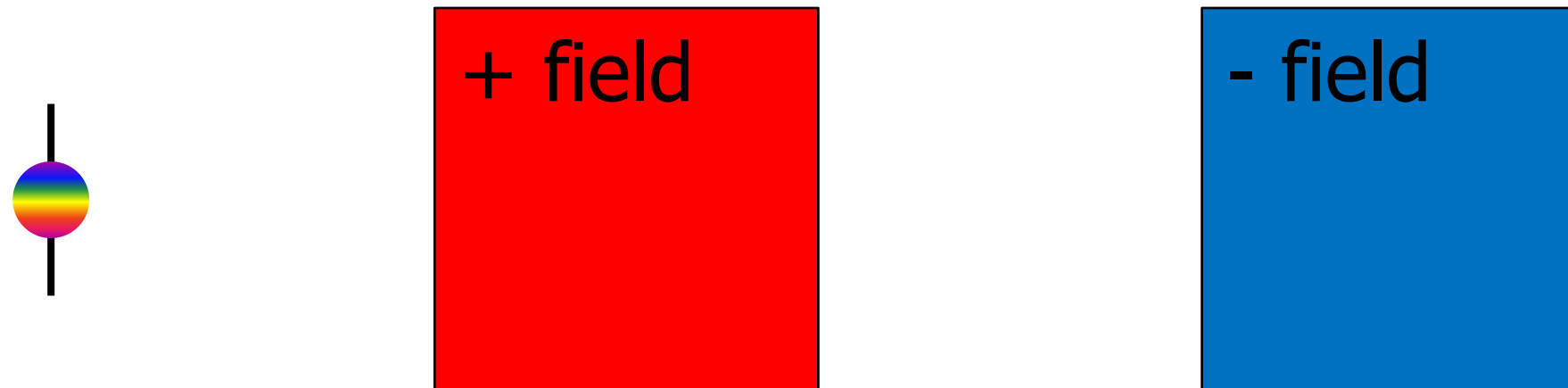
C) Measuring In Real Space

SANS vs SESANS

- Sensitivity:
1 nm – 500 nm
 - Length instrument:
12 – 80 m
 - Reciprocal space
- Sensitivity:
30 nm – 20 μm
 - Length instrument:
5 m
 - Real space



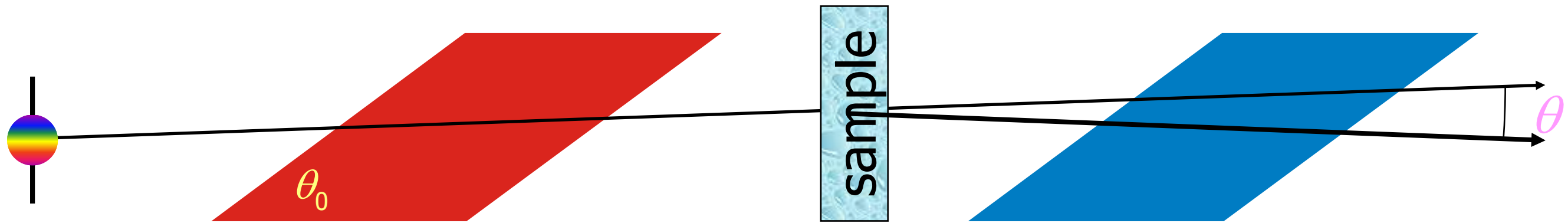
Larmor precession neutron spin magnetic field



Precession proportional to magnetic field line integral:

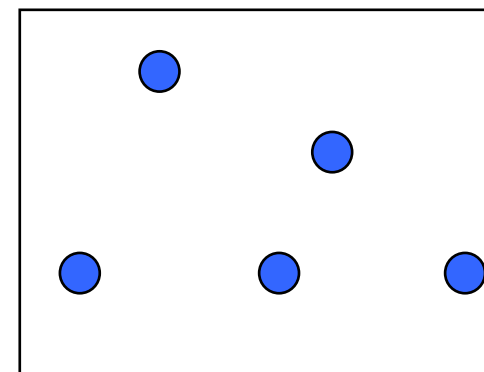
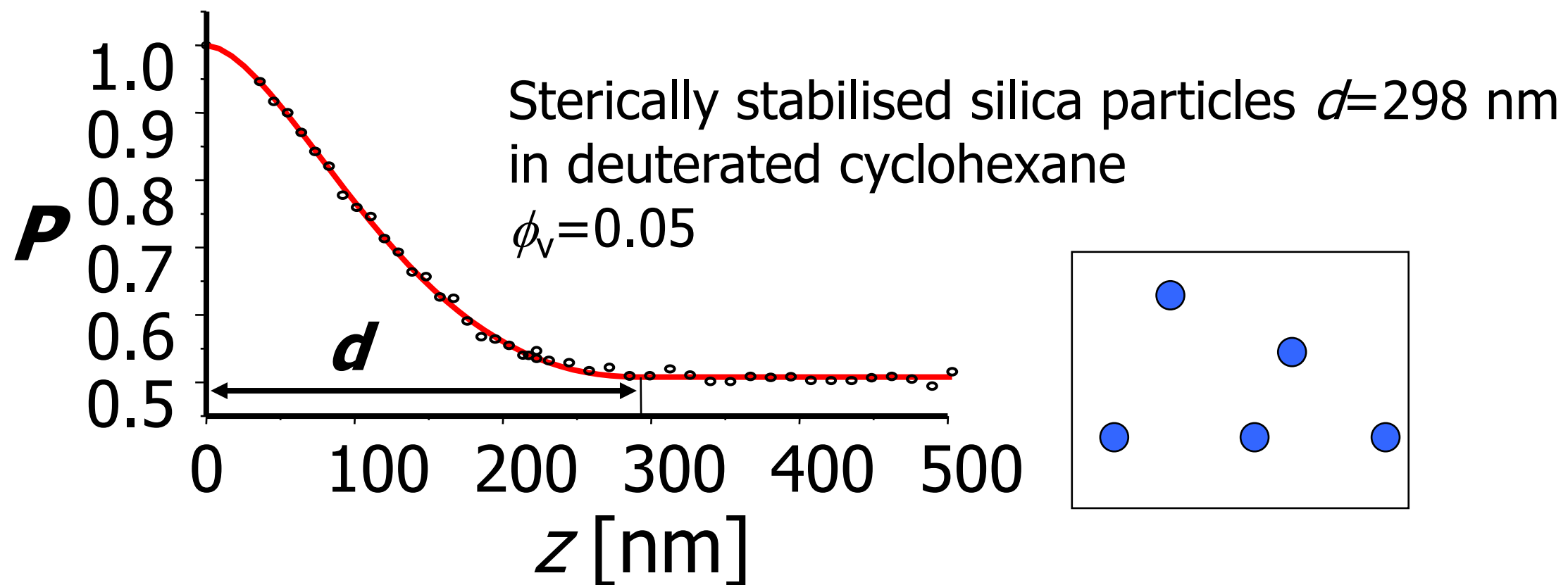
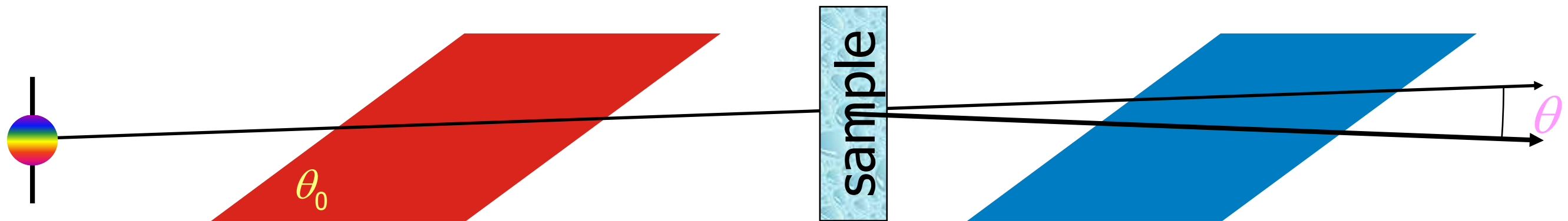
$$\phi \propto \int B dL$$

Larmor encoding of scattering angle spin-echo small angle neutron scattering



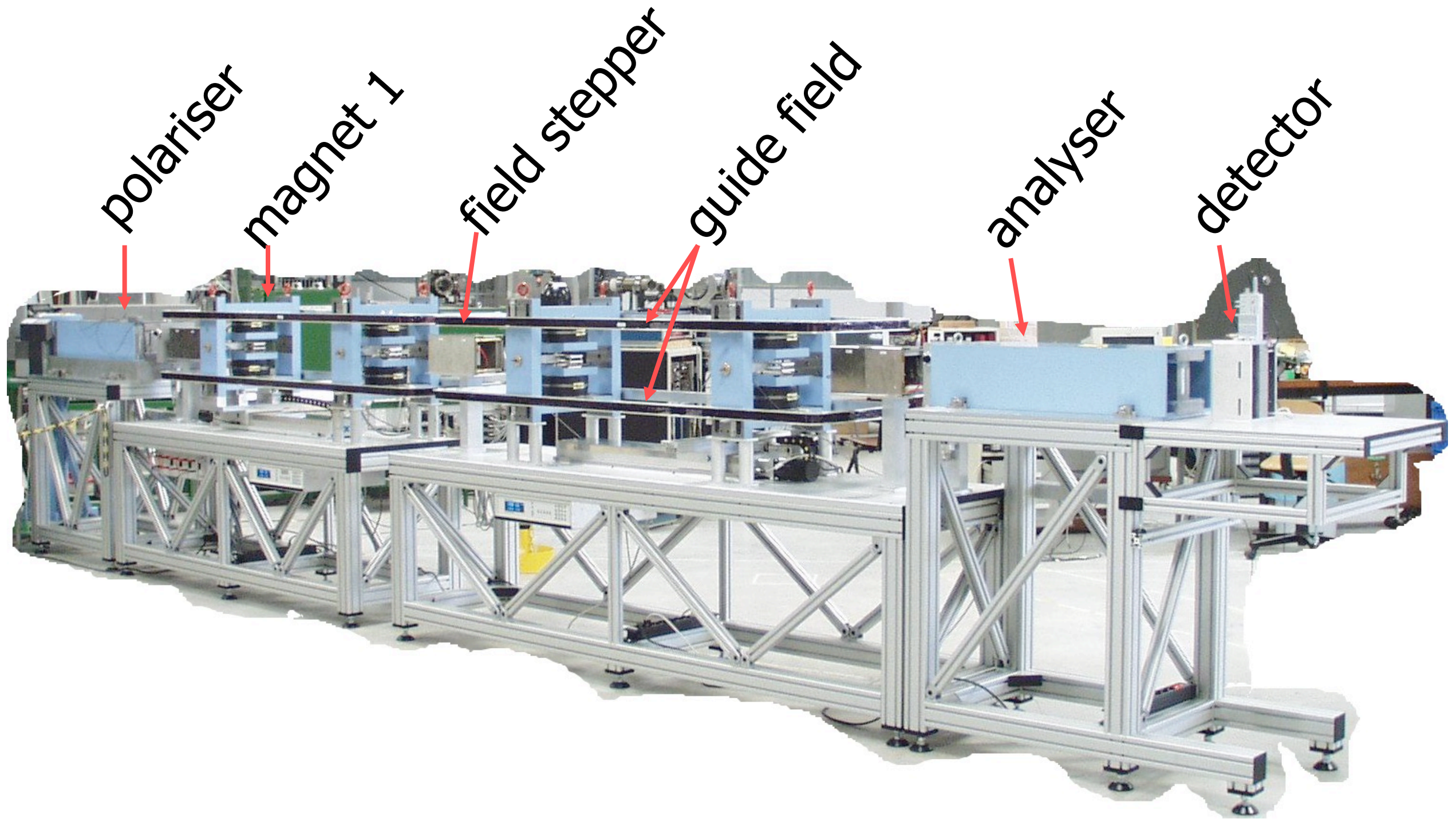
- Unscattered beam gives spin echo $\phi = 0$
independent of height and angle
- Scattering by sample
 - ❑ no complete spin echo
 - ❑ net precession angle
- High resolution with divergent beam, sensitive to scattering over $3 \mu\text{rad}$

SESANS = Fourier transform scattering \Rightarrow
projected density correlation function



SESANS

spin-echo small-angle neutron scattering



Spin-Echo SANS (SESANS)

Real Space Information...

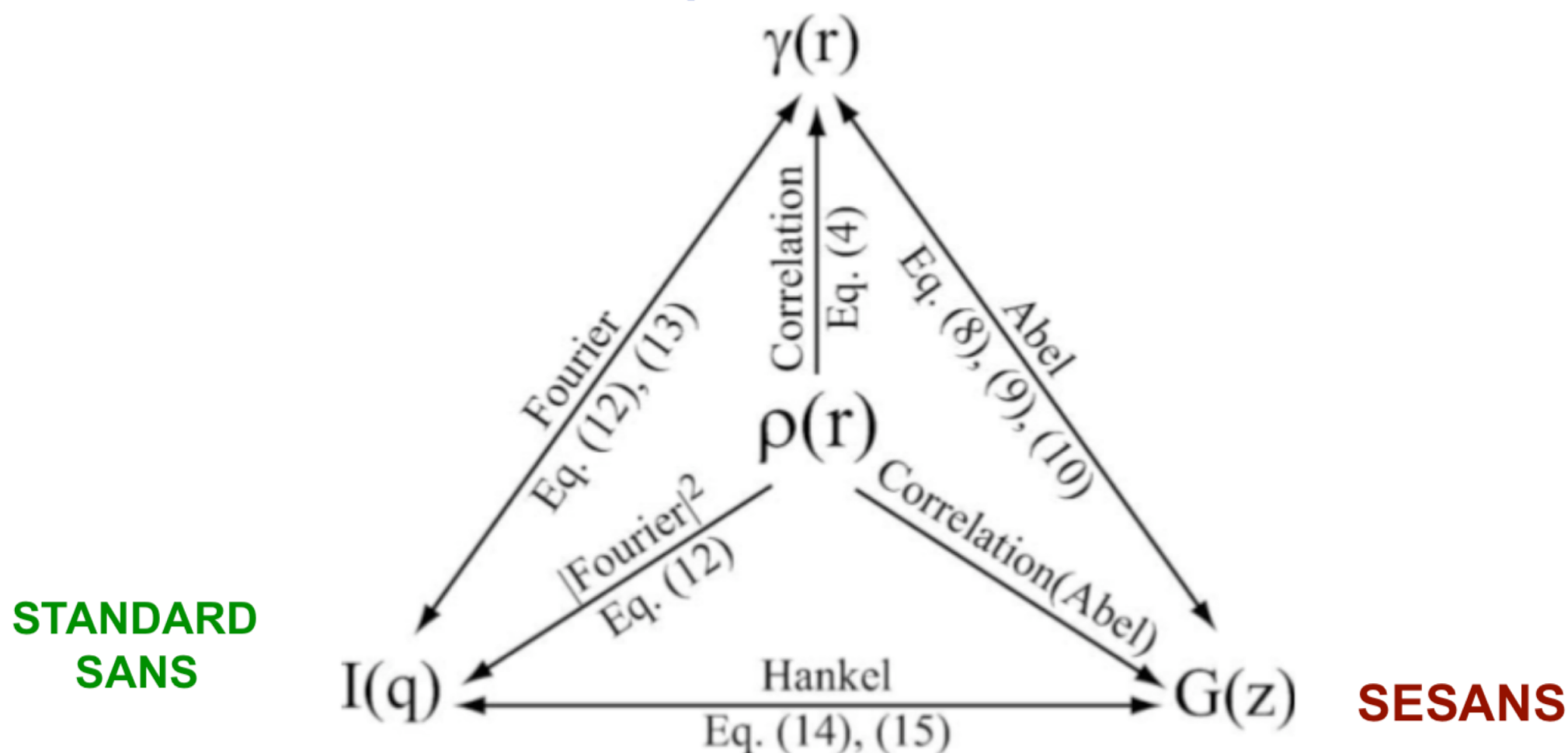
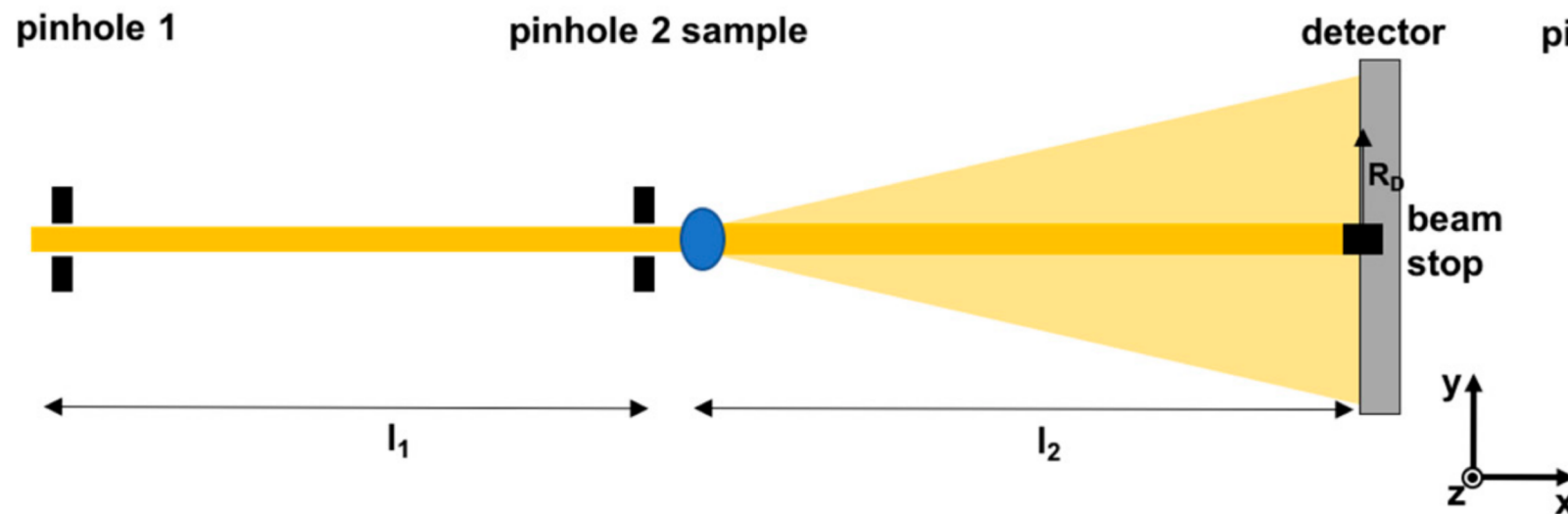


Figure 1

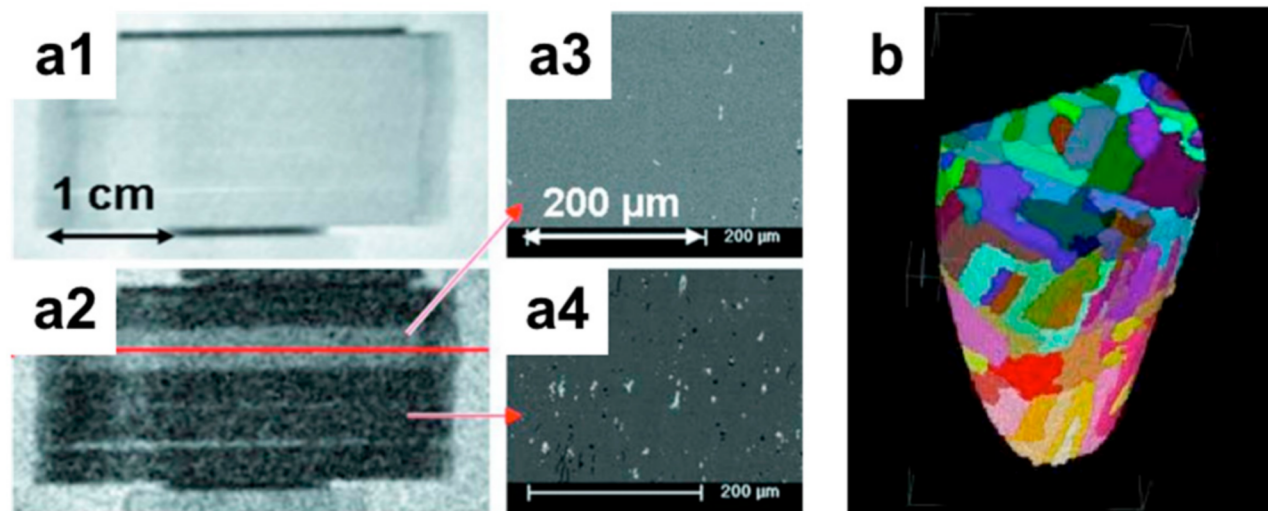
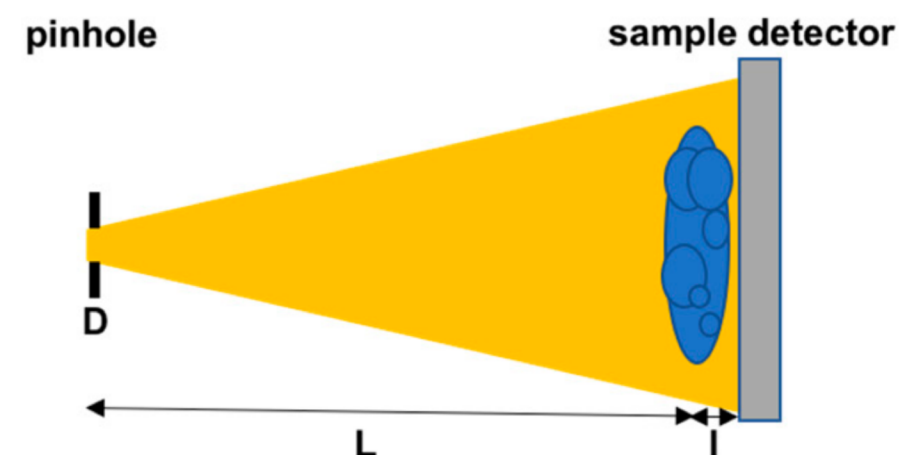
The relationship between the Abel, Hankel and Fourier transformations for an isotropic distribution $\rho(r)$. Note that $G(z)$ can be found by calculating the autocorrelation function of the projection of $\rho(r)$.

SANS Imaging – Dark Field / Phase Contrast Imaging

SANS

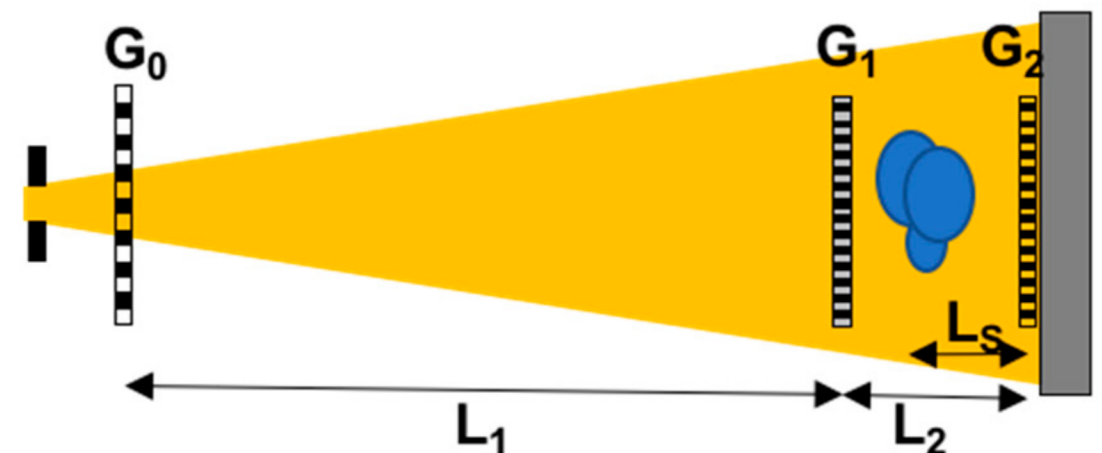


Imaging



Qualitative dark-field imaging: (a) materials distinguished by scattering originating from precipitates and porosity. (b) visualizing magnetic domain walls in 3D.

Talbot-Lau



Summary

Many methods exist that extend pinhole SANS measurements to examine structure on longer length scales and short time scales.

These are generally available at only a few facilities and require more specialist support and planning than a normal SANS instrument.

Questions?